

# Reliability and Availability of Particle Accelerators: Concepts, Lessons, Strategy

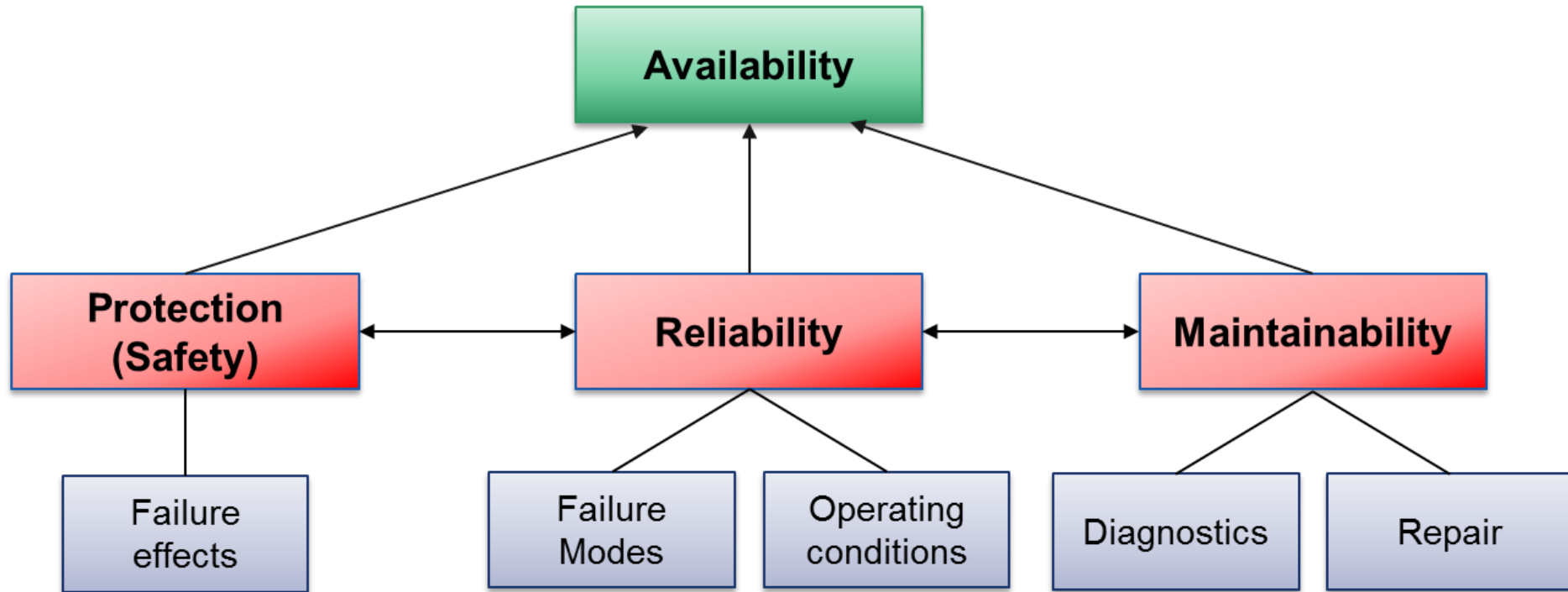
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Xbeam Strategy Workshop– 15/02/2017

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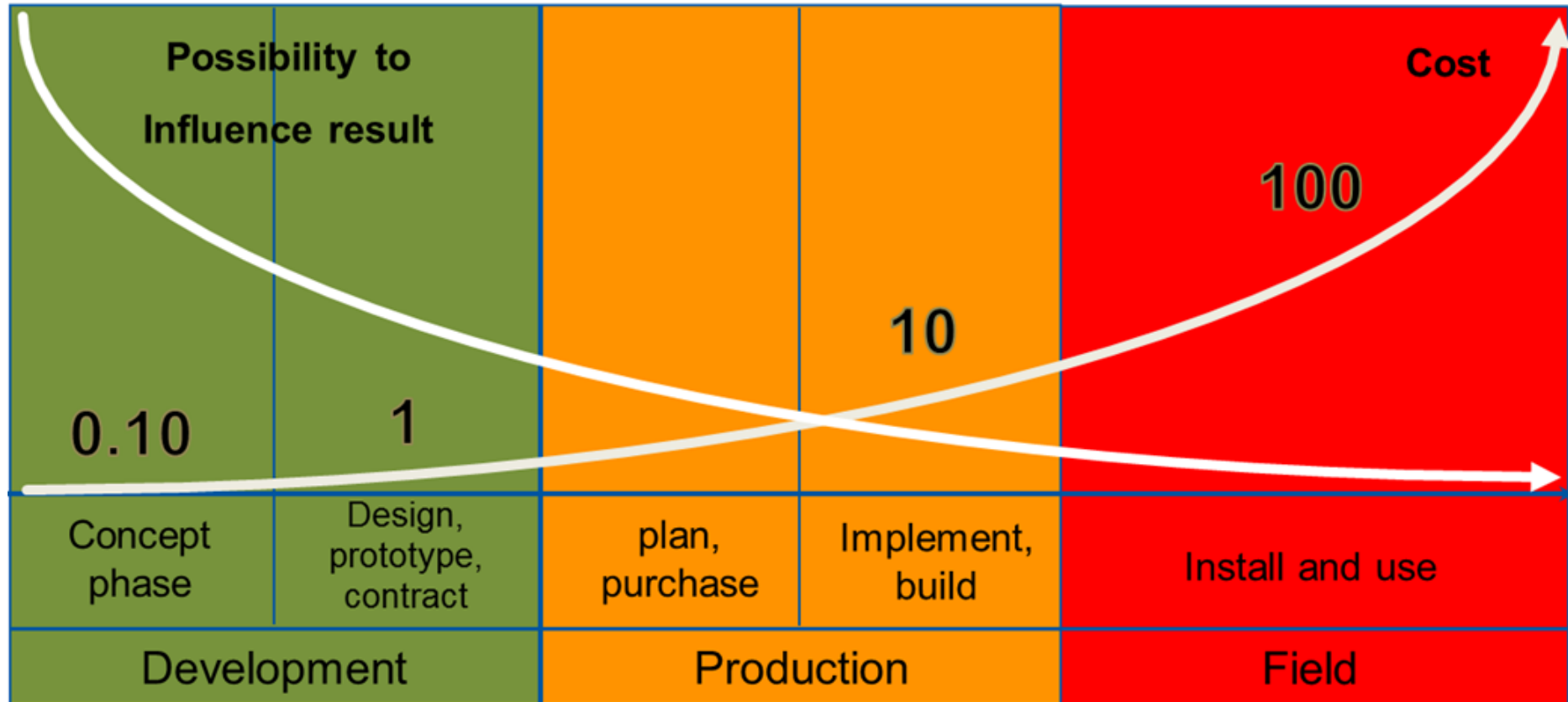
Acknowledgements: R. Schmidt, B. Todd, M. Kwiatkowski, F. Bouly, A. Lechner, A. Niemi, J. Gutleber.



**NB: in the context of particle accelerators, we speak about ‘Protection’ rather than ‘Safety’, if no personnel is involved**

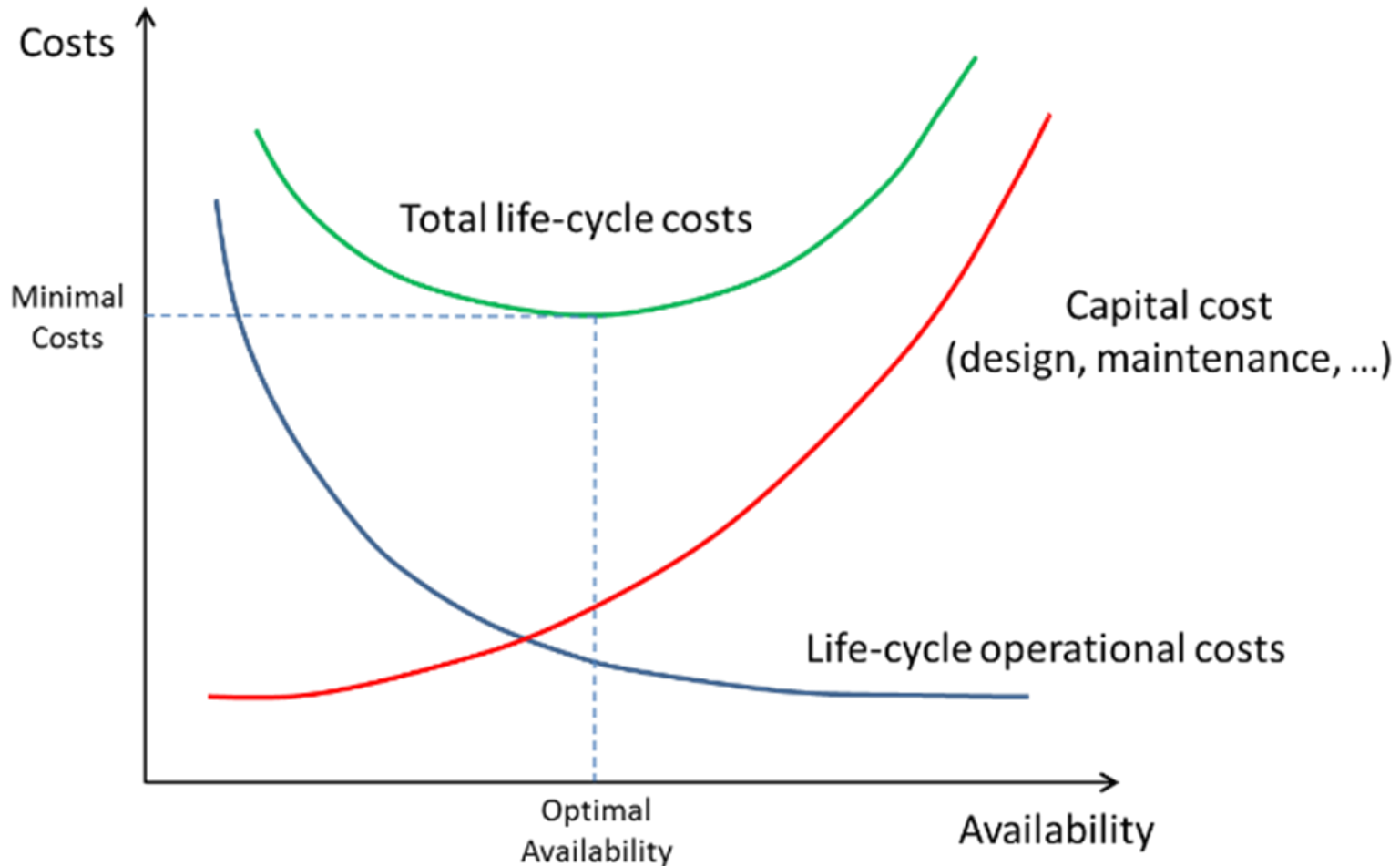
- **Reliability (0-1)** is the probability that a system does not fail during a defined period of time under given functional and environmental conditions
  - Example of reliability specification: “An accelerator must have a reliability of 60 % after 100 h in operation, at an operating current of 40 mA”
  
- **Availability (0-1)** is the probability that a system in a functional state at given point in time
  - Example of availability specification: “An accelerator must ensure beam delivery to a target for 90 % of the scheduled time for operation”

- Product/Accelerator Lifecycle



- The earlier reliability constraints are included in the design, the more effective the resulting measures will be

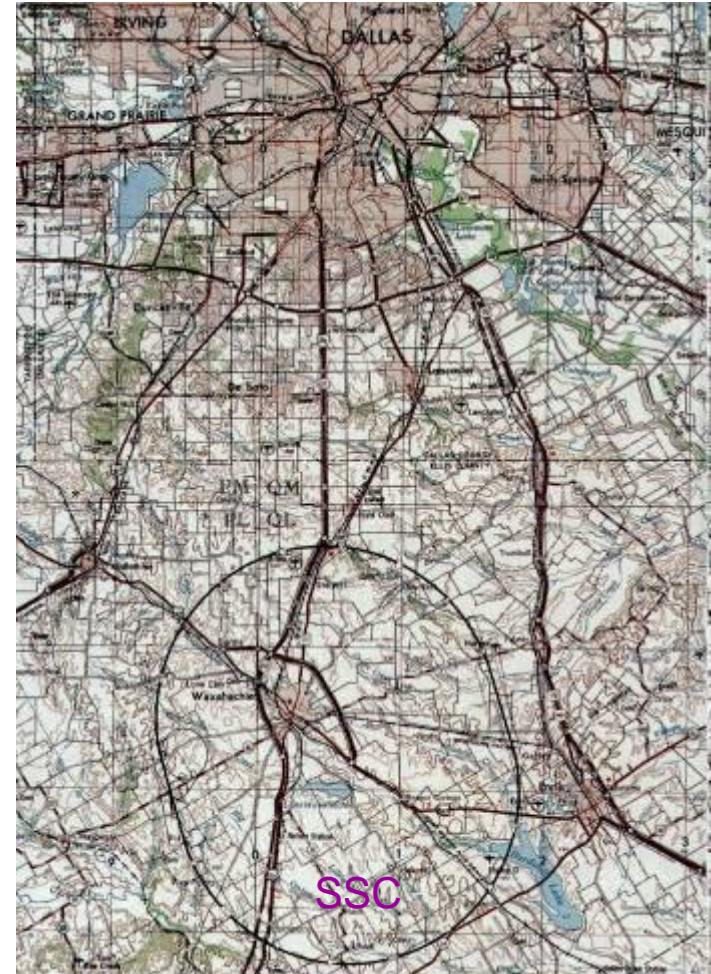
# Importance of Reliability Analyses



- Given a target performance reach (neutron fluence, number of patients treated, luminosity production, ...), an optimal balance between capital costs and operational costs must be found

# Risk

- **Not to complete** the construction of the accelerator
  - Happened to other projects, the most expensive was the Superconducting Super Collider in Texas / USA with a length of ~80 km
  - Cost increase from 4.4 Billion US\$ to 12 Billion US\$, US congress stopped the project in 1993 after having invested more the 2 Billion US\$
- **Not to be able to operate** the accelerator
- **Damage** to the accelerator **beyond repair** due to an accident



# Energy stored in the LHC



Picture source: [http://en.wikipedia.org/wiki/File:Alstom\\_AGV\\_Cerhenice\\_img\\_0365.jpg](http://en.wikipedia.org/wiki/File:Alstom_AGV_Cerhenice_img_0365.jpg)

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Picture source: [http://militarytimes.com/blogs/scoopdeck/2010/07/07/the-airstrike-that-](http://militarytimes.com/blogs/scoopdeck/2010/07/07/the-airstrike-that-never-happened/)

[never-happened/](http://militarytimes.com/blogs/scoopdeck/2010/07/07/the-airstrike-that-never-happened/)

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$3 \cdot 10^{14}$  protons in each beam

Kinetic Energy of 200 m Train at 155

km/h  $\approx$  360 MJoule

Stored energy per beam is 360 MJ

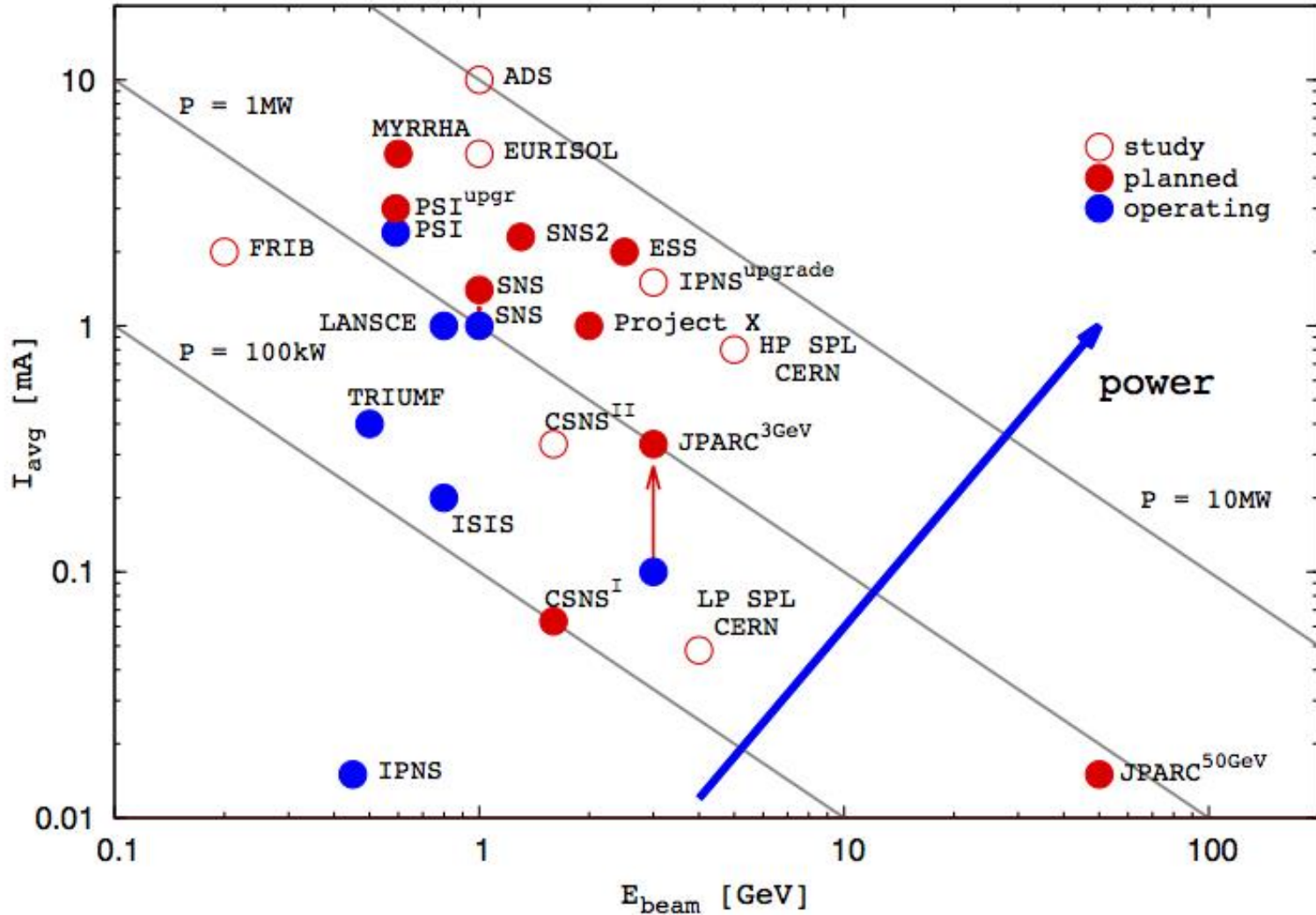


Stored energy in the magnet circuits  
is 9 GJoule

Kinetic Energy of Aircraft Carrier at  
50 km/h  $\approx$  9 GJoule

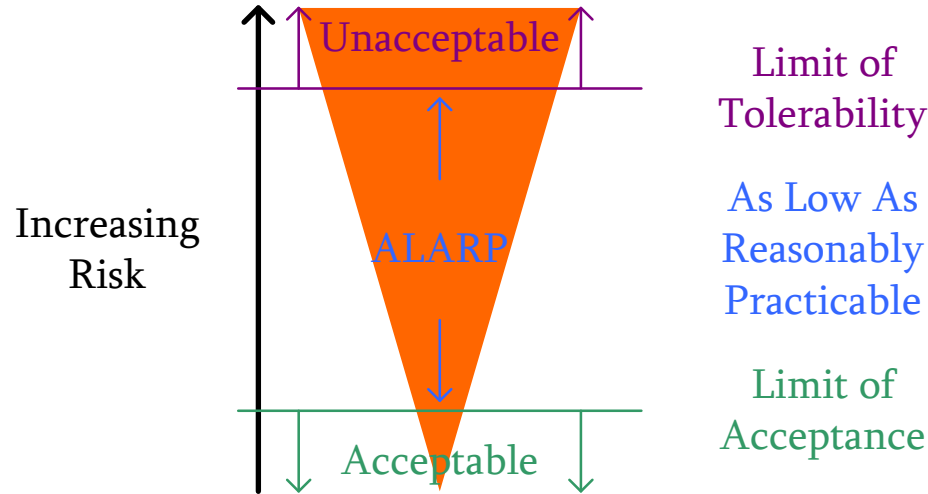
....can melt 14 tons of copper





# Risk Assessment (1/2)

B. Todd, M. Kwiatkowski, "Risk and Machine Protection for Stored Magnetic and Beam Energies"



- Risk is the product of the probability of occurrence of an undesired event x its impact (financial, reputation, downtime,...)
- 'Acceptable' or 'Unacceptable' risk depends on the context!  
Different for user-oriented facilities, medical accelerators, fundamental research,...

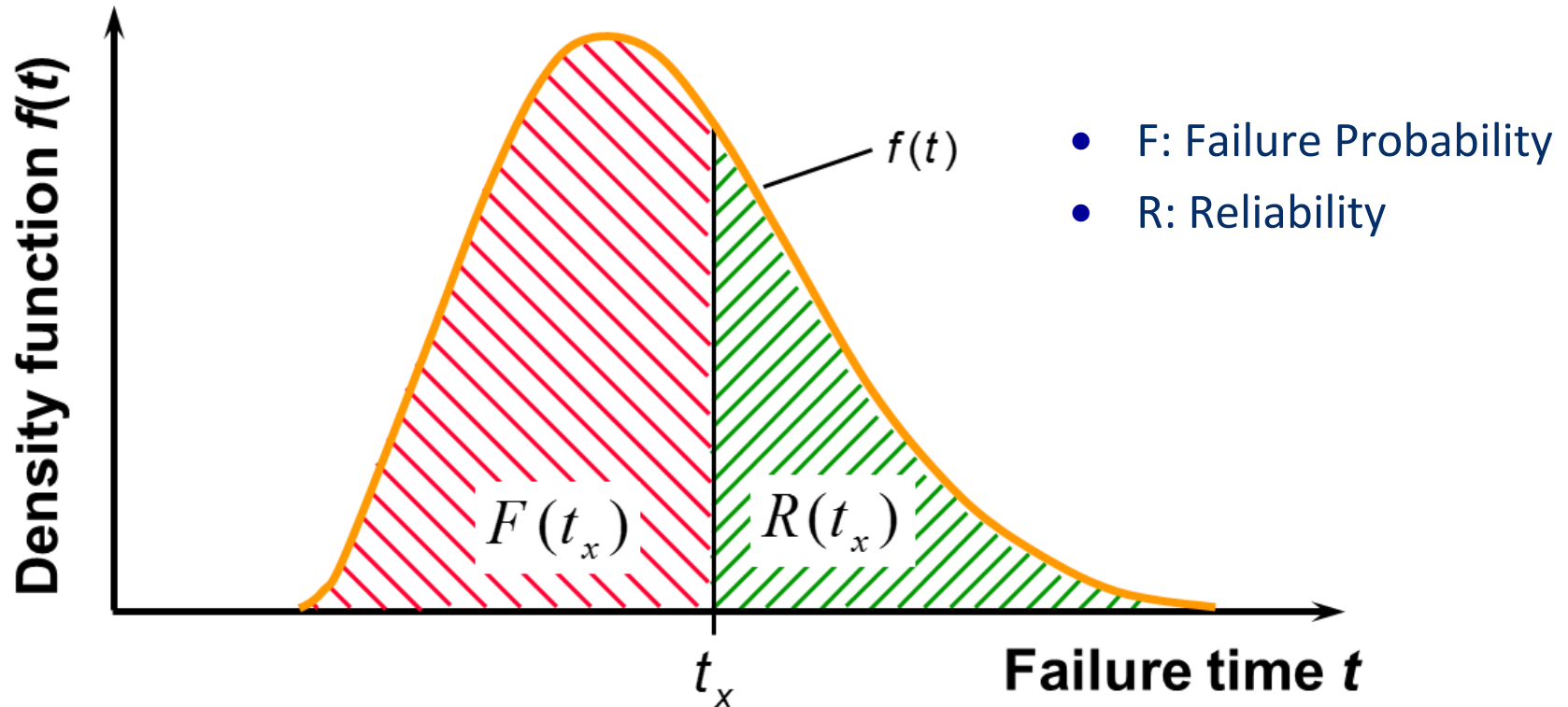
# Risk Assessment: Example

Machine Protection Concern    **IMPACT**    Availability Concern

	1/year	Catastrophic	Major	Moderate	Low	Very Low
Very likely	10					
Frequent	1					
Probable	0.1					
Occasional	0.01					
Remote	0.001					
Improbable	0.0001					
Cost [MCHF]		> 50	1-50	0.1-1	0.01-0.1	0-0.01
Downtime [days]		> 180	20-180	3-20	1-3	0-1

- **IMPORTANT:** this matrix depends on the application!

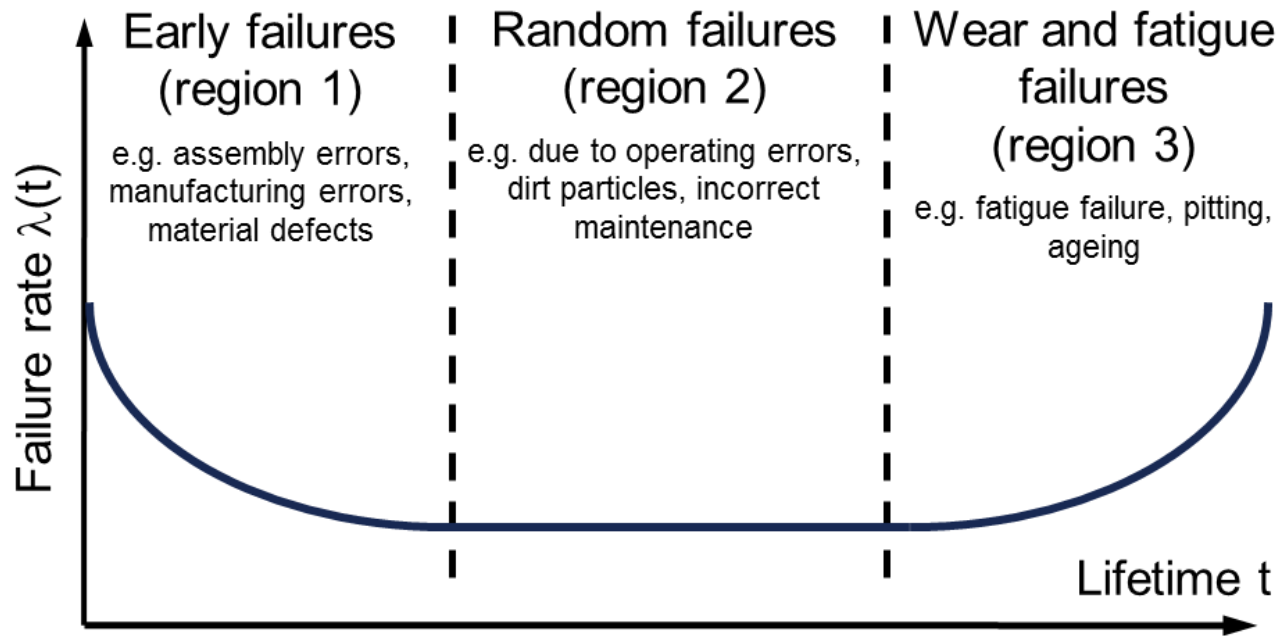
# Failure Frequency



- The failure behaviour of a component is described by a density function
- Its integral over a certain time  $t_x$  gives the failure probability
- Reliability is the complement to 1 of the Failure Probability ('Survival' Probability)

# Failure Rate and Bathtub Curve

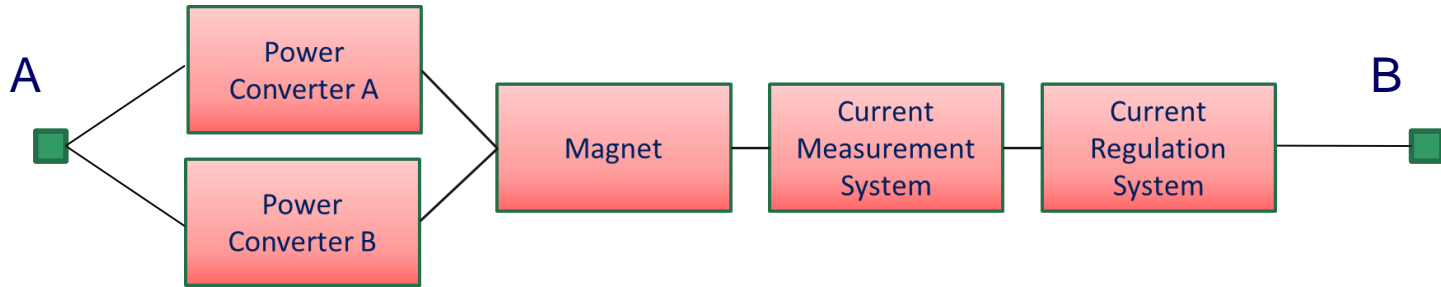
$$\lambda(t) = \frac{\text{Failures}}{\text{Total number of units still intact}} = \frac{f(t)}{R(t)}$$



- In practice, it is often assumed that failures occur randomly, i.e. they are described by an exponential density function → **constant failure rate  $\lambda$**
- Only in the latter case Mean Time Between Failures (MTBF) =  $1/\lambda$
- Clearly a **simplification** in some cases...

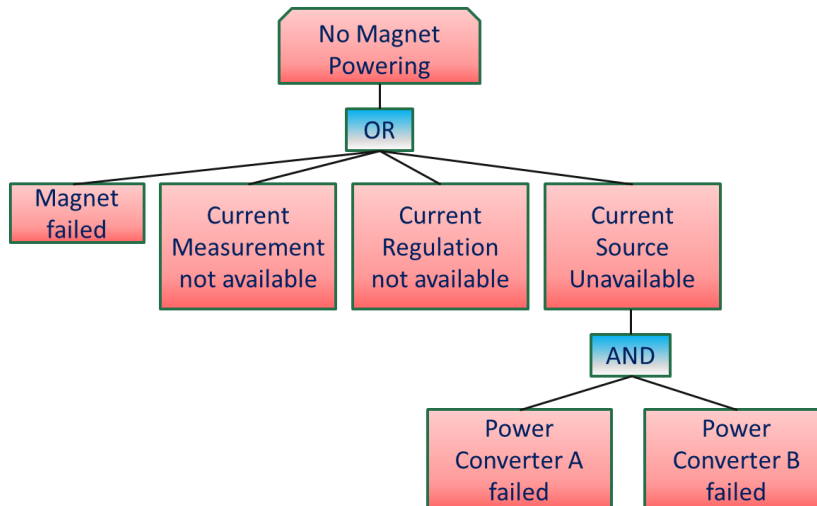
- Reliability Block Diagram:

Question: what is the minimum set of components that allows fulfilling the system functionality?



- Fault Tree:

Question: what are the combinations of failures that lead to a system failure?



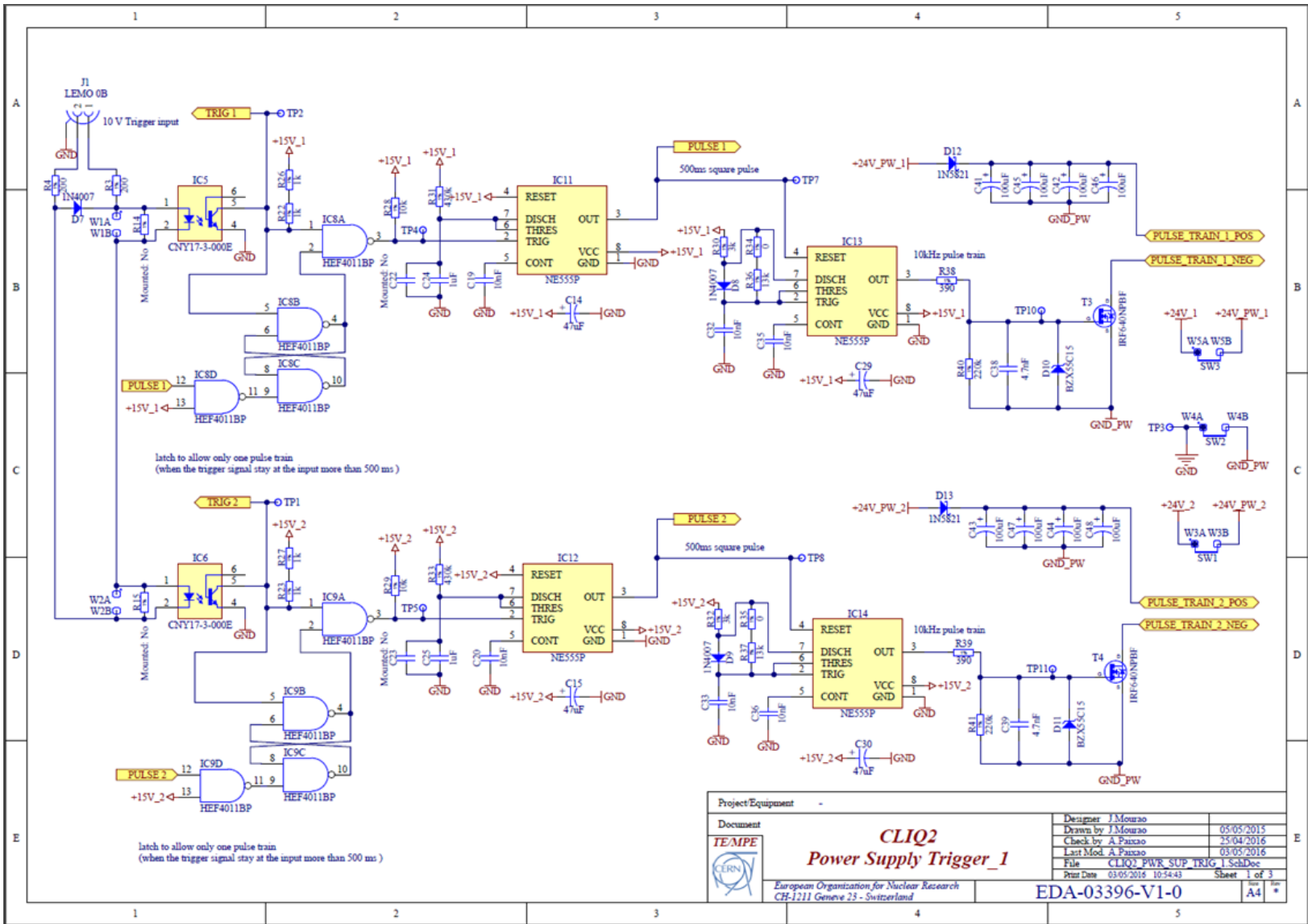
Boolean Algebra allows calculating system reliability from component reliability

- Tests:
  - Large number of samples to be tested / long time for testing
  - May be impractical in some cases
  - Accelerated lifetime tests (if applicable)
- Experts' estimates
  - Big uncertainties on boundary conditions
  - Good approximation for known technologies
  - Good for preliminary estimates
- Using Standards (Mil. Handbooks for electronic components)
  - Very systematic approach
  - Boundary conditions can be taken into account (quality of components, environment)
  - Difficult to follow technology advancements (e.g. electronics)

**IMPORTANT:** The power of these methods is not in the accuracy of failure rate estimates, but in the possibility to compare architectures and show the sensitivity of system performance on reliability figures



# Example of Failure Rate Calculations





# Example of Failure Rate Calculations

CLIQ unit

- CLIQ UNIT:FR=4120 FITS
  - UECCPS24P501104-5:HV CAPACITOR CHARGER:FR=1000
  - E56.C82-406900:CAPACITOR 600 V/ 40 mF:FR=200
  - 0.3:TRIGGERING SYSTEM:FR=2920(CR=0.207)
  - CS10.241:TC POWER SUPPLY:FR=1531
  - 0.3.2:TRIGGER CARD:FR=262.2(CR=1.725)
    - 200:RESISTOR:FR=33.41
    - 1N4007:PLASTIC RECTIFIER:FR=9.301
    - CNY17-3-000E:PHOTOTRANSISTOR OPTOCOPLER:FR=80
    - HEF4011BP:QUAD 2-INPUT NAND GATE:FR=11.2
    - NE555P:TIMER:FR=1.4
    - BZX55C15:ZENER DIODE:FR=9.465
    - IRF640NPBF:TRANSISTOR MOSFET:FR=77.72
    - 1N5821:SCHOTTKY DIODE:FR=10.87
    - 036 RSP:POLARICED ELECTROLYTIC CAPACITOR:FR=27.11
    - 0.3.3:PULSE TRANSFORMER:FR=1077
    - 5STB24N2800:BI-DIRECTIONAL CONTROL THYRISTOR:FR=49.1

Prediction blocks - General - Top 1000 rows

ID	Part number	Description	Parent
	UECCPS24P5011...	HV CAPACITOR CHARGER	
	E56.C82-406900	CAPACITOR 600 V/ 40 mF	
0.3	0-3	TRIGGERING SYSTEM	
CS10.241	0-3-1	TC POWER SUPPLY	
0.3.2	0-3-2		
200	0-3-2-1		
1N4007	0-3-2-2		
CNY17-3-000E	0-3-2-3		
HEF4011BP	0-3-2-4		
NE555P	0-3-2-5		
BZX55C15	0-3-2-6		
IRF640NPBF	0-3-2-7		

Block Properties - IRF640NPBF : TRANSISTOR MOSFET MIL-217 [F2] Transistor, LF FET

General Parameters Rate/Pi Factors Tasks Notes Hyperlink

Quantity: 1

Application, LF: Linear

Environment: Ground, benign

Quality, Discrete Semicon: Jan

Junction Temperature: 54.8

Junction Temp Calc Mode: Full Model

Ambient Temperature: 30

Case Temperature: 42.4

Operating Power (W): 0.4

Connection Type: Reflow Solder

Adjustment Factor: 1

Type, FE: MOS FET

No of Pins: 3

Theta Case / Ambient: 31

Theta Junction Case: 31

Stress= Temp= OK Cancel

International Rectifier

IRF640N/S/LPbF

International Rectifier

Conditions

$I_D = 250\mu A$   
to 25°C,  $I_D = 1mA$   
 $I_D = 11A$   $\Phi$   
 $I_D = 250\mu A$   
 $I_D = 11A$   $\Phi$   
 $V_{GS} = 0V$   
 $V_{GS} = 0V, T_J = 150^\circ C$

$V_{DS} = 200V$   
 $R_{DS(on)} = 0.15\Omega$   
 $I_D = 18A$

Conditions

$I_D = 11A, V_{GS} = 0V$   $\Phi$   
 $I_D = 11A$   
 $\Delta I/\Delta t$   $\Phi$   
Transition is dominated by  $L_C + L_D$

Conditions

symbol  $\Phi$   
the  $\Phi$   
verse  $\Phi$   
in diode  $\Phi$   
 $I_D = 11A, V_{GS} = 0V$   $\Phi$   
 $I_D = 11A$   
 $\Delta I/\Delta t$   $\Phi$   
Transition is dominated by  $L_C + L_D$

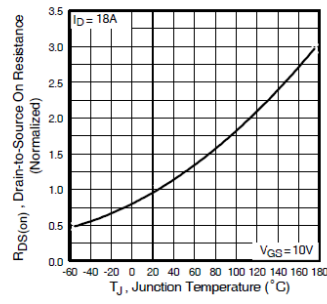
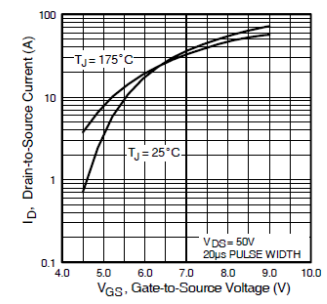
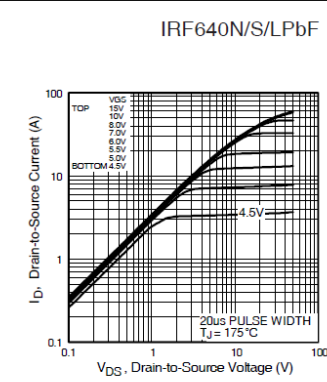
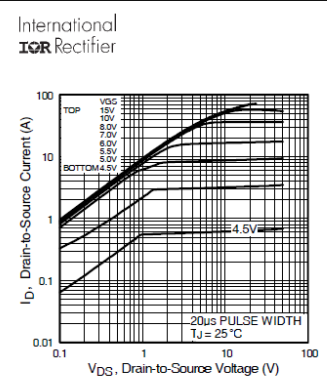
Max. Units

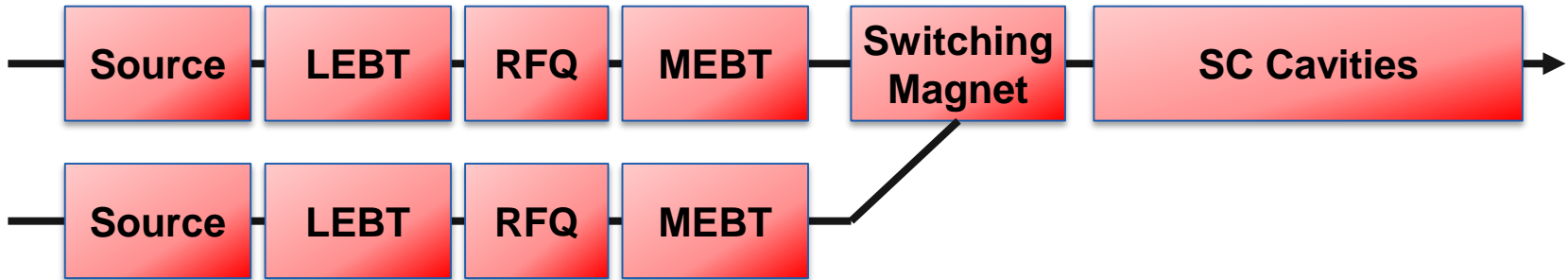
18	A
13	A
72	A
150	W
1.0	W/°C
± 20	V
247	mJ
18	A
15	mJ
8.1	V/ns
to +175	°C

07/23/10

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3





The switching magnet becomes the reliability bottleneck in this architecture

- It should be designed for high reliability
- How should it be operated? (only when required, at predefined times,...)

A strategy has to be defined on how to operate the 'spare' Linac:

- Continuously running – 'hot spare' (quantify operation costs)
- When required (consider additional time to recover nominal operation)

When introducing redundancy, think about remaining single points of failure!

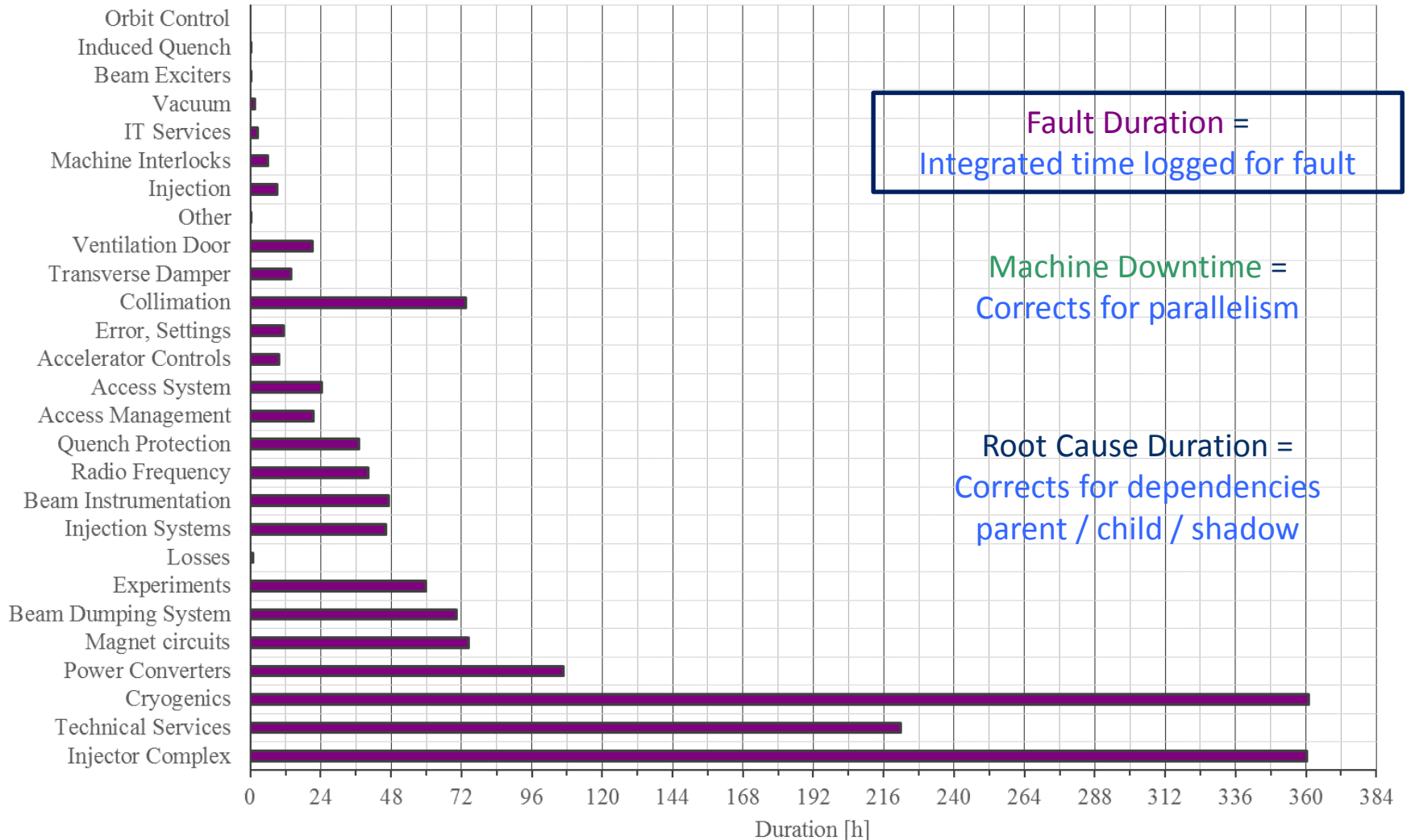
# Failure Impact: Downtime

# Accelerator Downtime

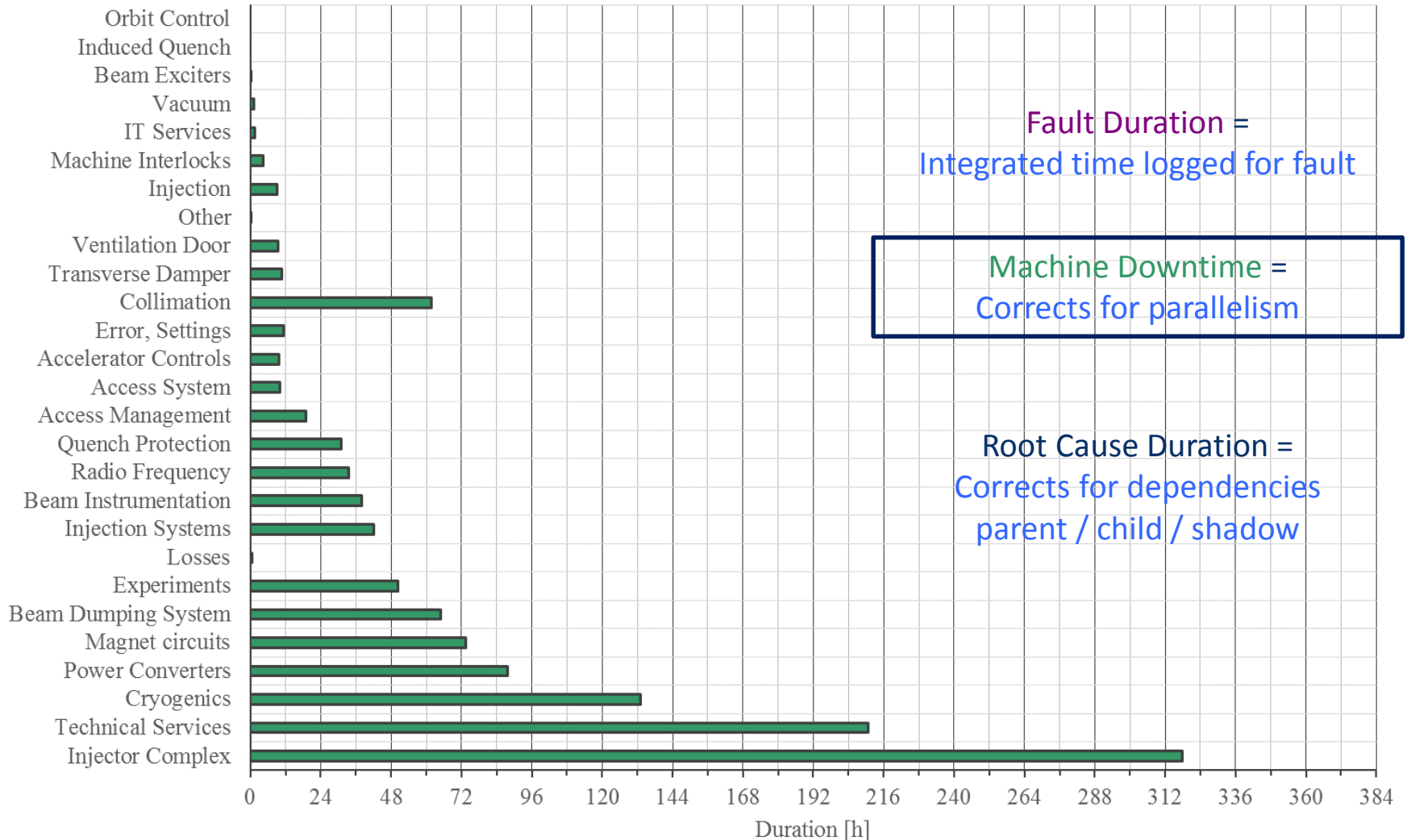


**Systematic follow-up of failures** → learn from experience → possible reduction of recovery times (faster diagnostics, faster repairs, management of spare parts,...)

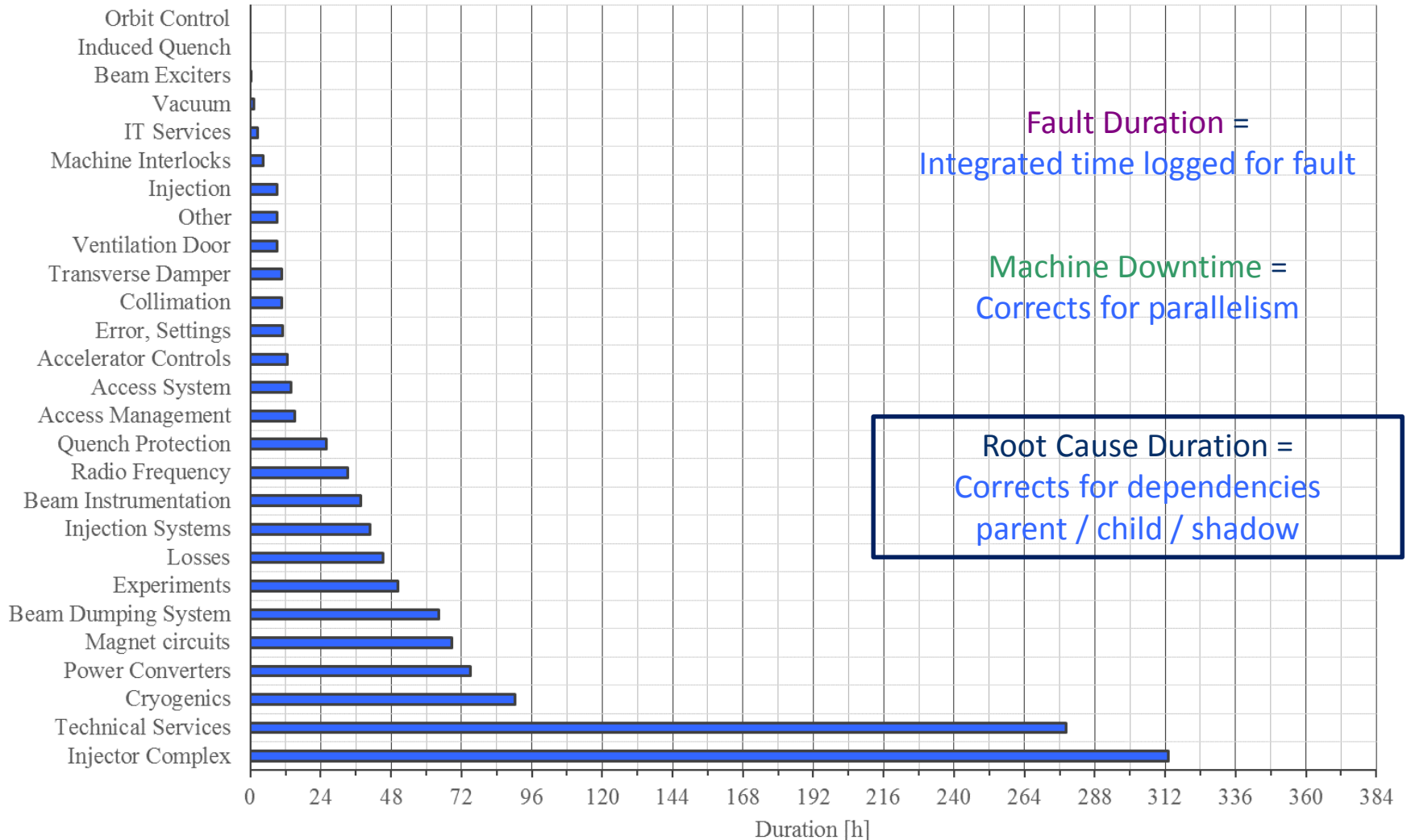
Stacked Pareto - Fault Duration, Machine Downtime and Root Cause Duration vs Root Cause System



Stacked Pareto - Fault Duration, Machine Downtime and Root Cause Duration vs Root Cause System



Stacked Pareto - Fault Duration, Machine Downtime and Root Cause Duration vs Root Cause System

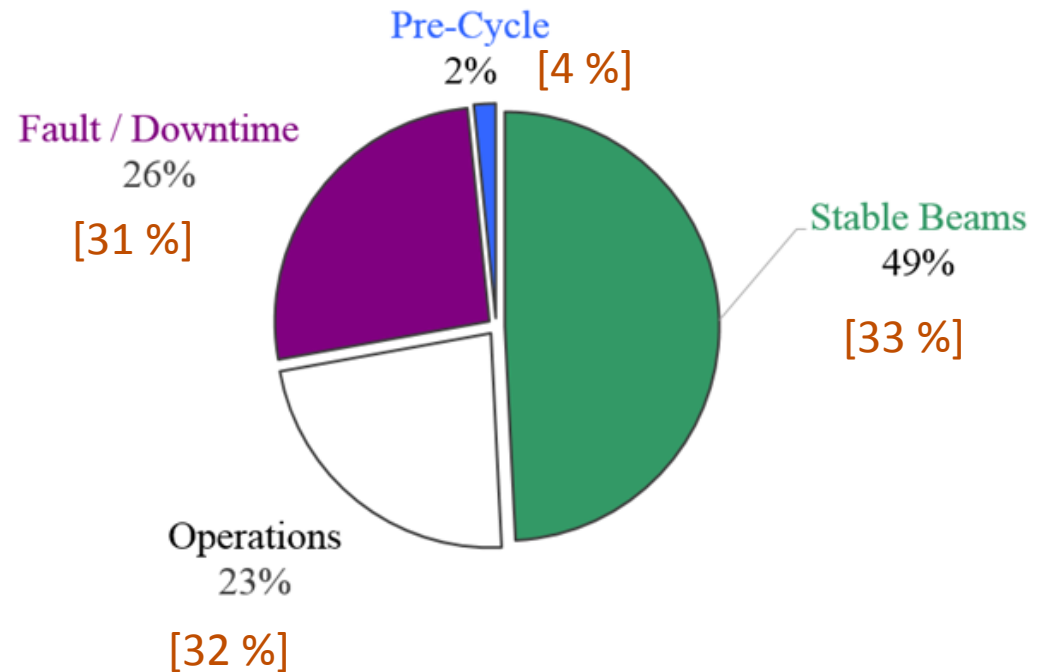




153 days physics  $\approx$  3738.7 hours

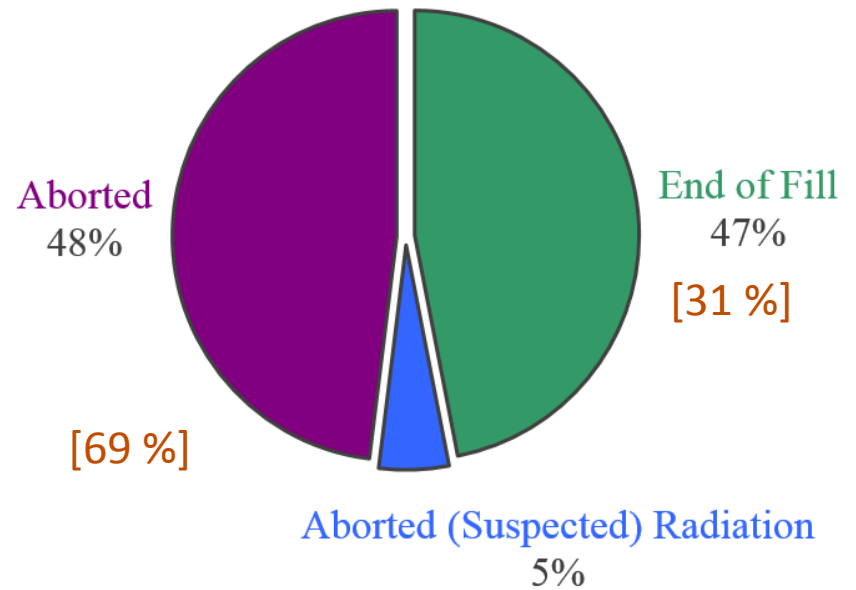
	Duration [h]
Stable Beams	1839.5
Fault / Downtime	980.0
Operations	857.9
Pre-Cycle	61.3
	= 3738.7

Operations contains nominal cycle + extra measurements (116h) + injection setting-up (23h) + some loss maps (35h) + planned accesses



[25 ns Run in 2015]

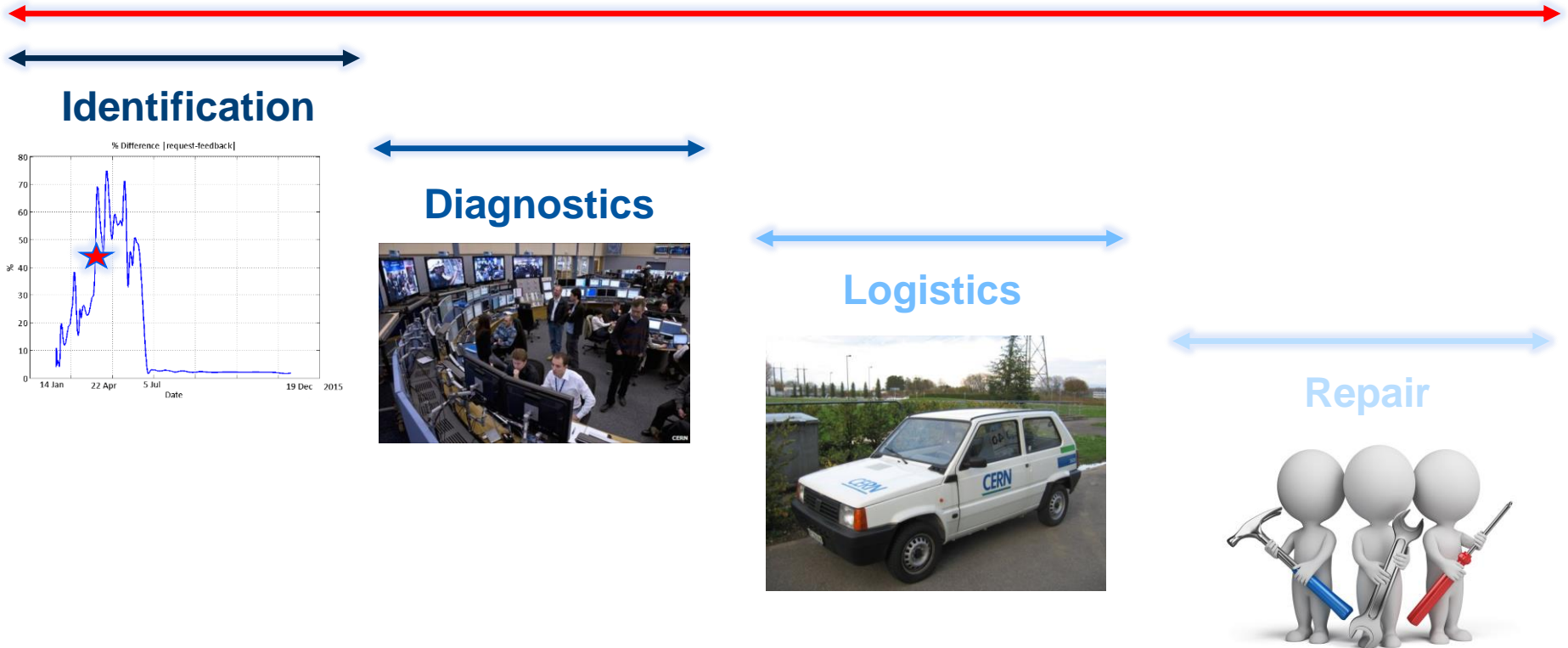
	[#]
Total Fills	762
Fills with Stable Beams	175
Fills with Physics in Adjust	4
→ End of Fill	84
→ Aborted	86
→ Aborted (suspected) R2E	9



[25 ns Run in 2015]

# Failure Duration

## Failure Duration



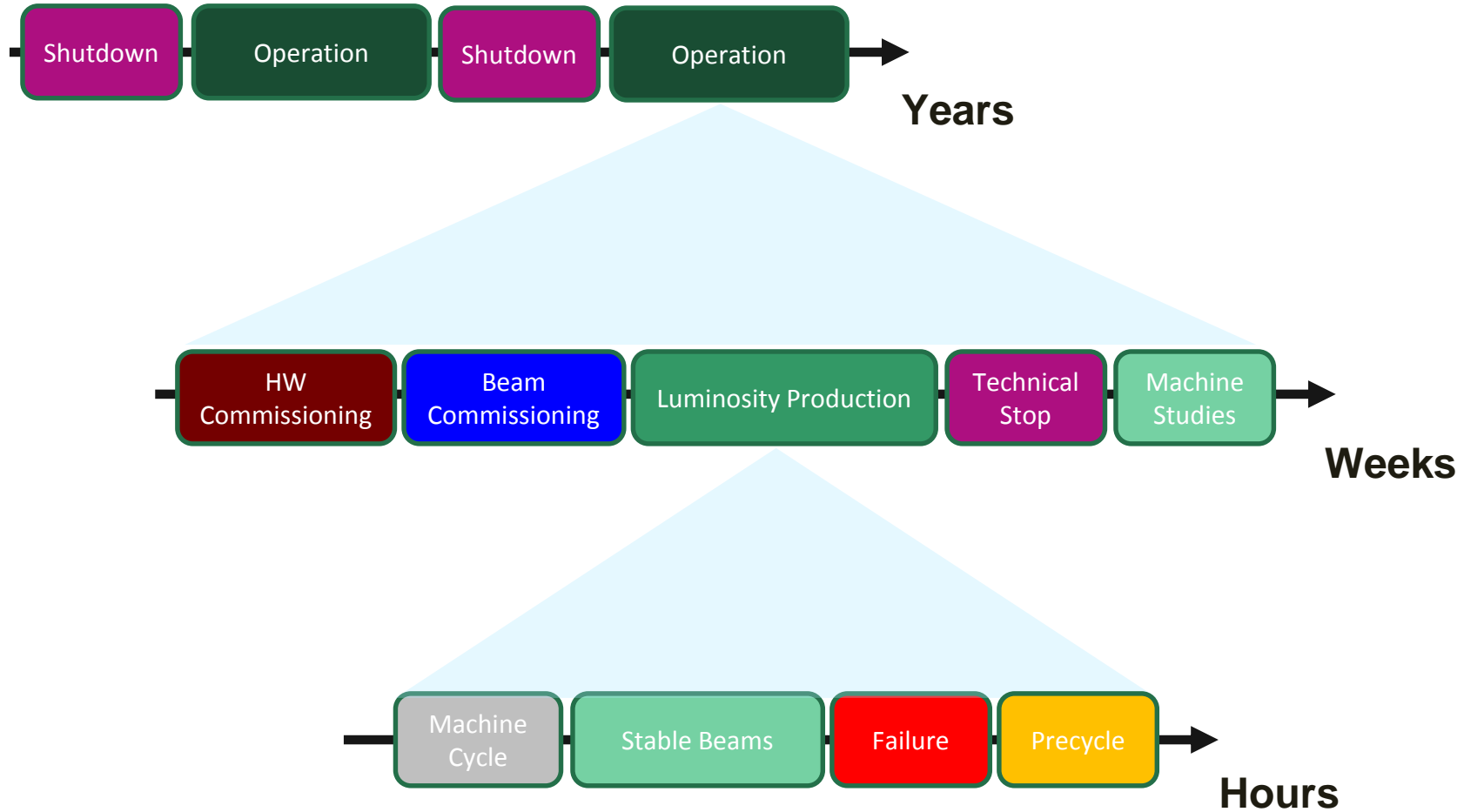
- **Mean Time to Repair (MTTR):** the average time required to repair a failed component or device.
- In addition, some time might be required to recover nominal operating conditions (e.g. beam-recommissioning, source stabilization, magnetic pre-cycles,...)

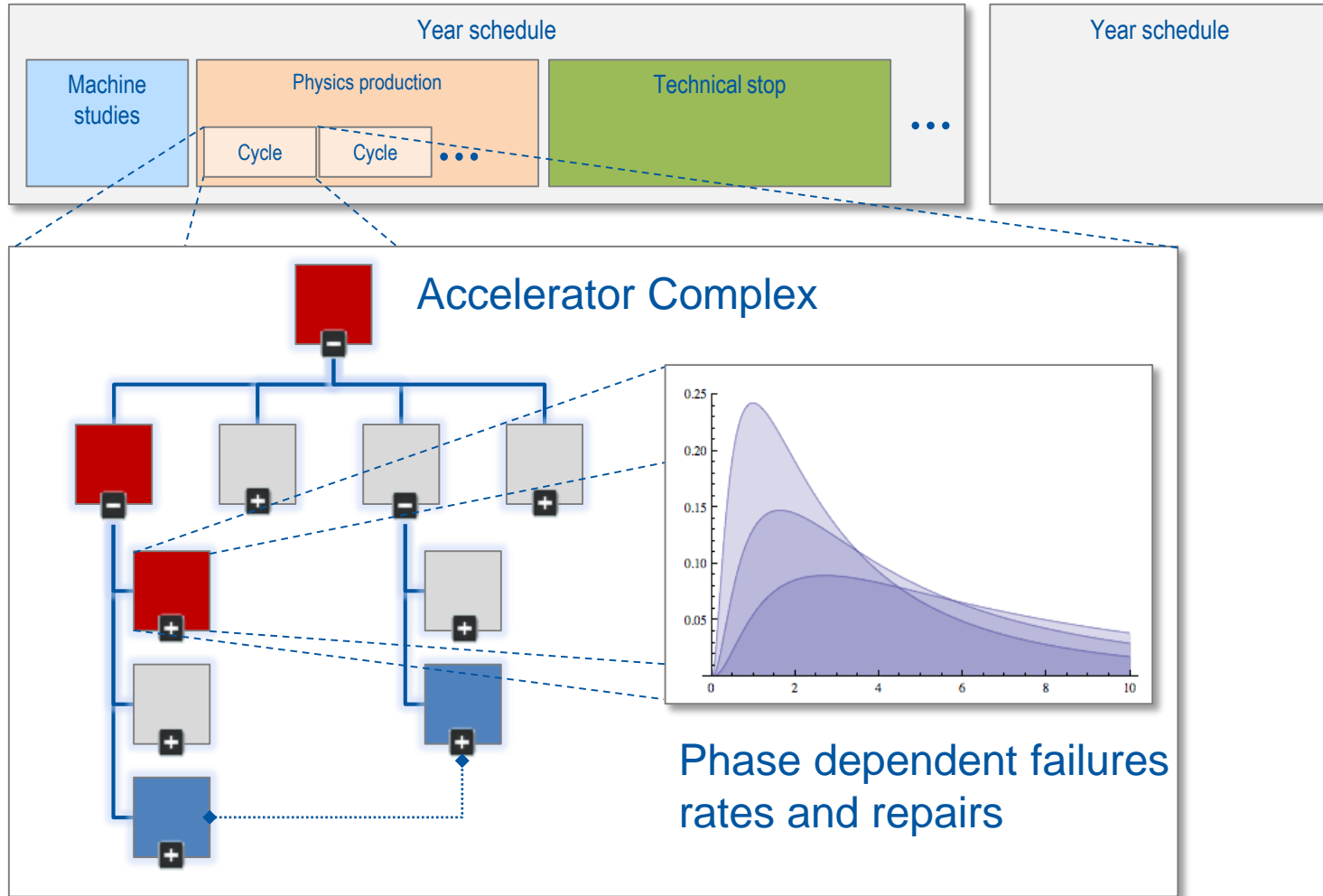


# Maintenance and Operability

- Maintenance and operability should be considered from **early design** phases of the accelerator
- System **architectures** can strongly influence maintainability
- **Modular designs** help optimizing maintenance tasks and commissioning
- **Accessibility** of equipment (when possible) ensures faster recoveries after failures
- Advanced **diagnostics** capabilities help identifying failure root causes
- Important: reliability analyses provide the means for **spare part management**

# From Reliability Data to Availability Modelling





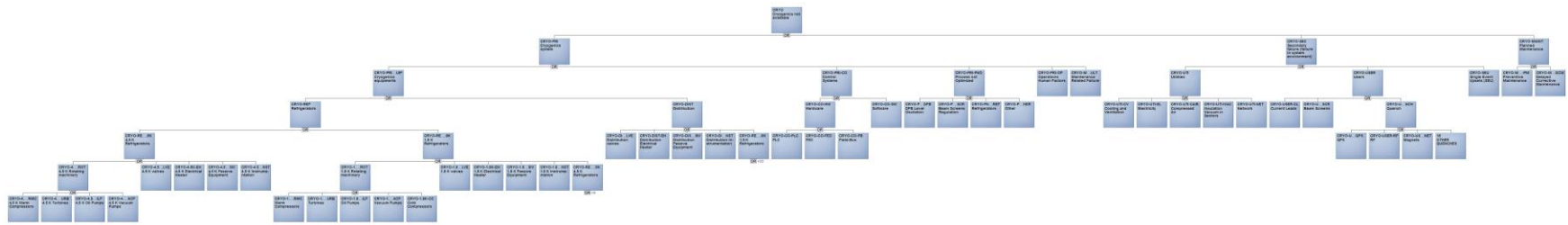
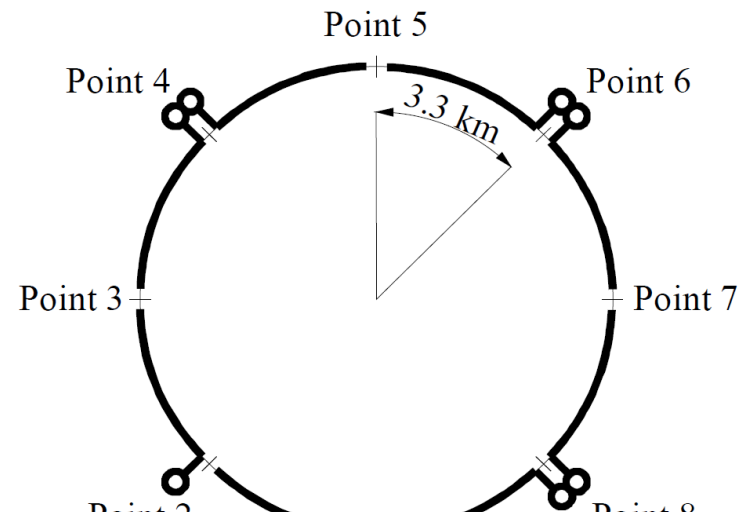
- Goal: Define faults that lead to loss of cryogenic conditions
- Built in collaboration with Cryo experts + E. Rogova from TU Delft
- Basis for current Cryo fault categories in logbooks

## Cryogenics system

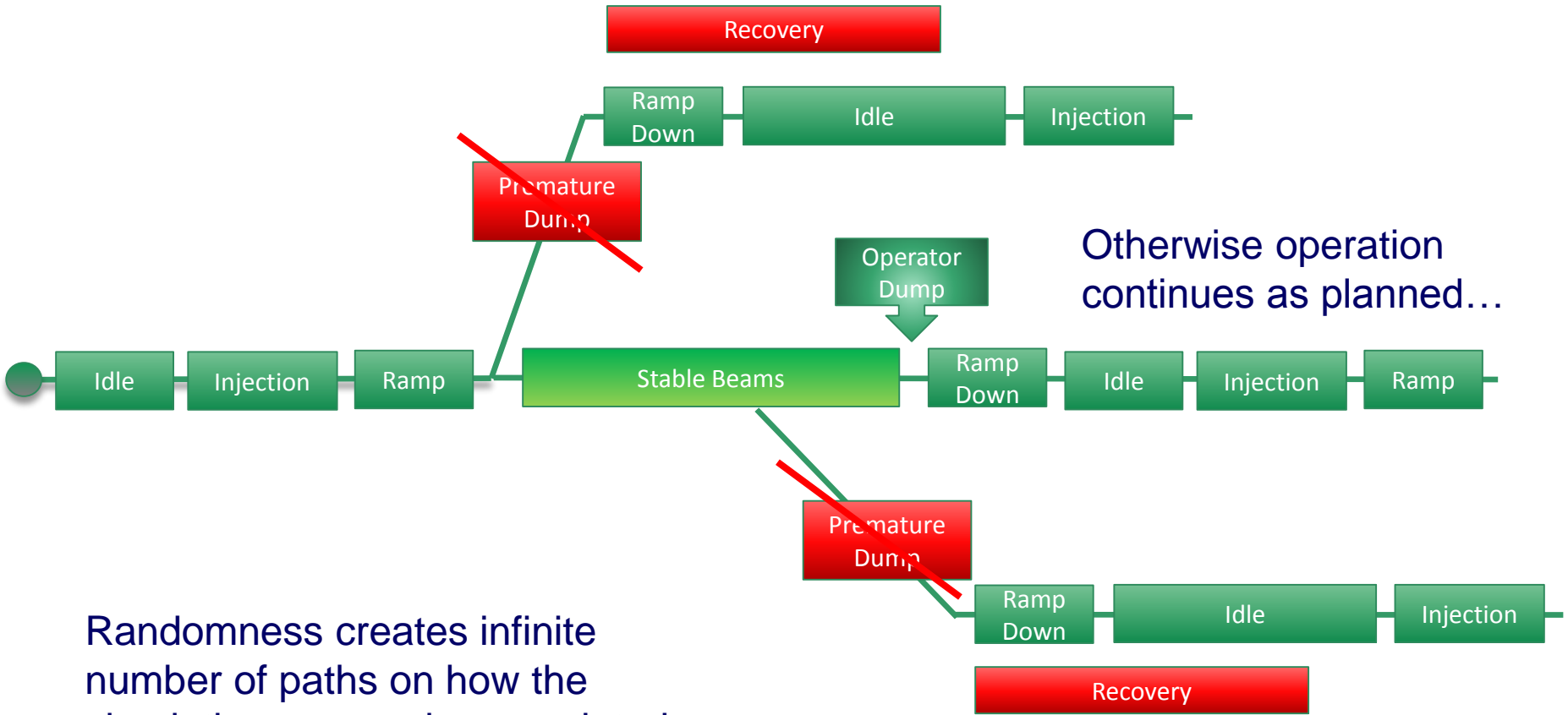
Primary faults

Secondary faults

- Users related failures
- Utility related failures

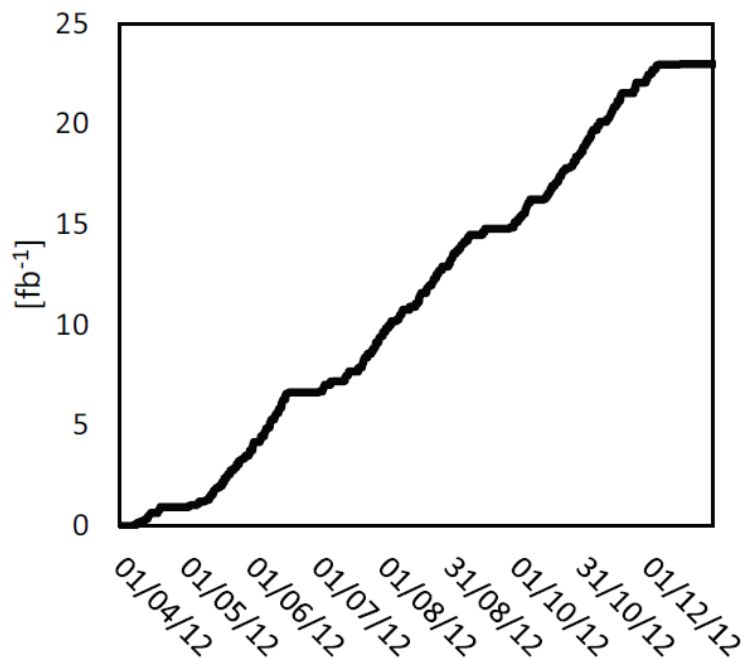




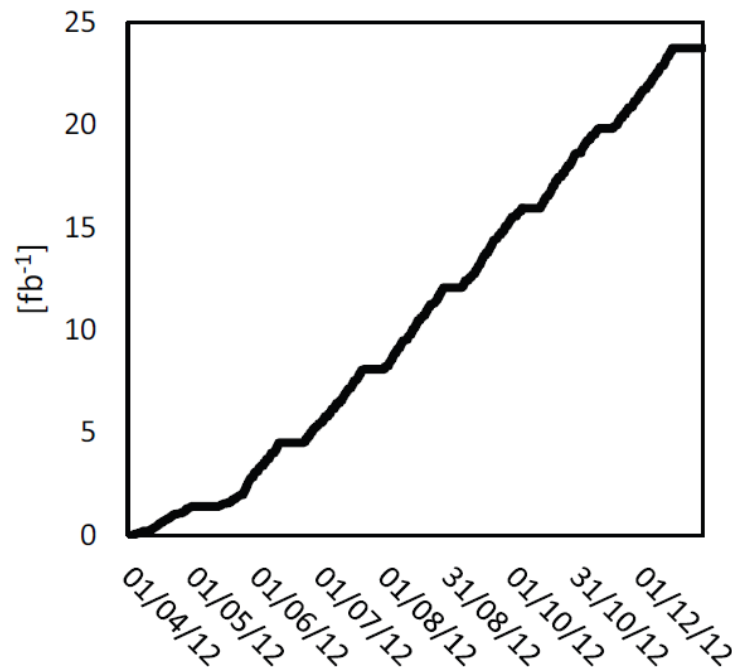


Randomness creates infinite number of paths on how the simulation run can be completed

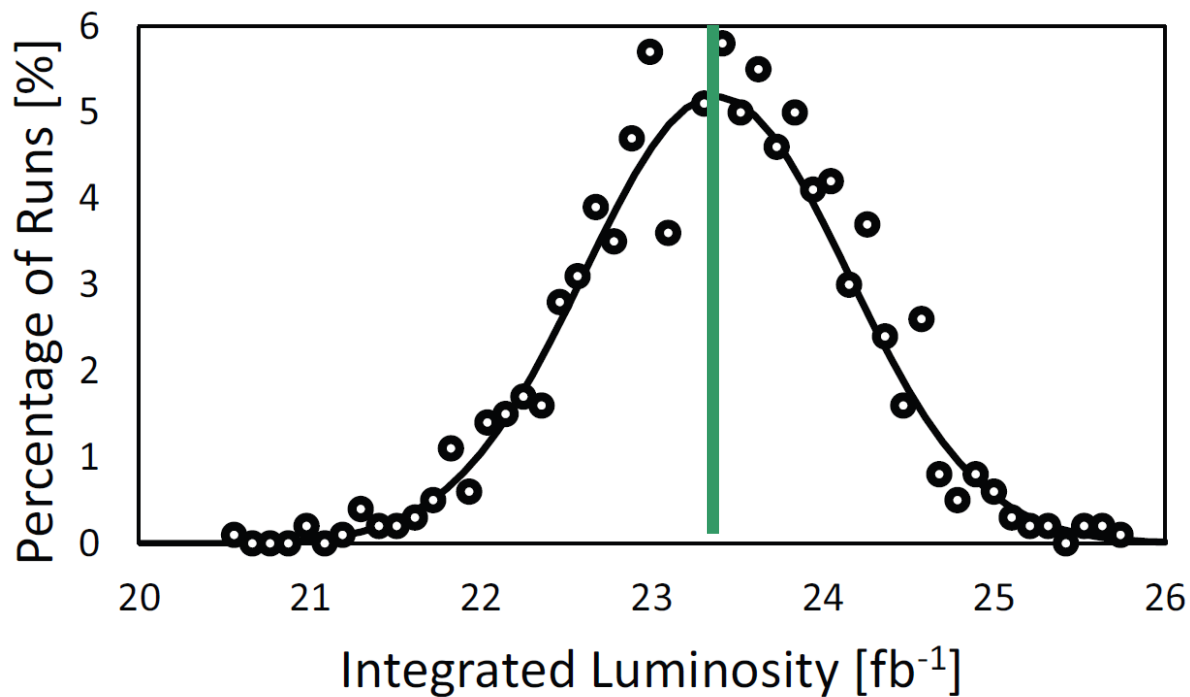
2012 luminosity production



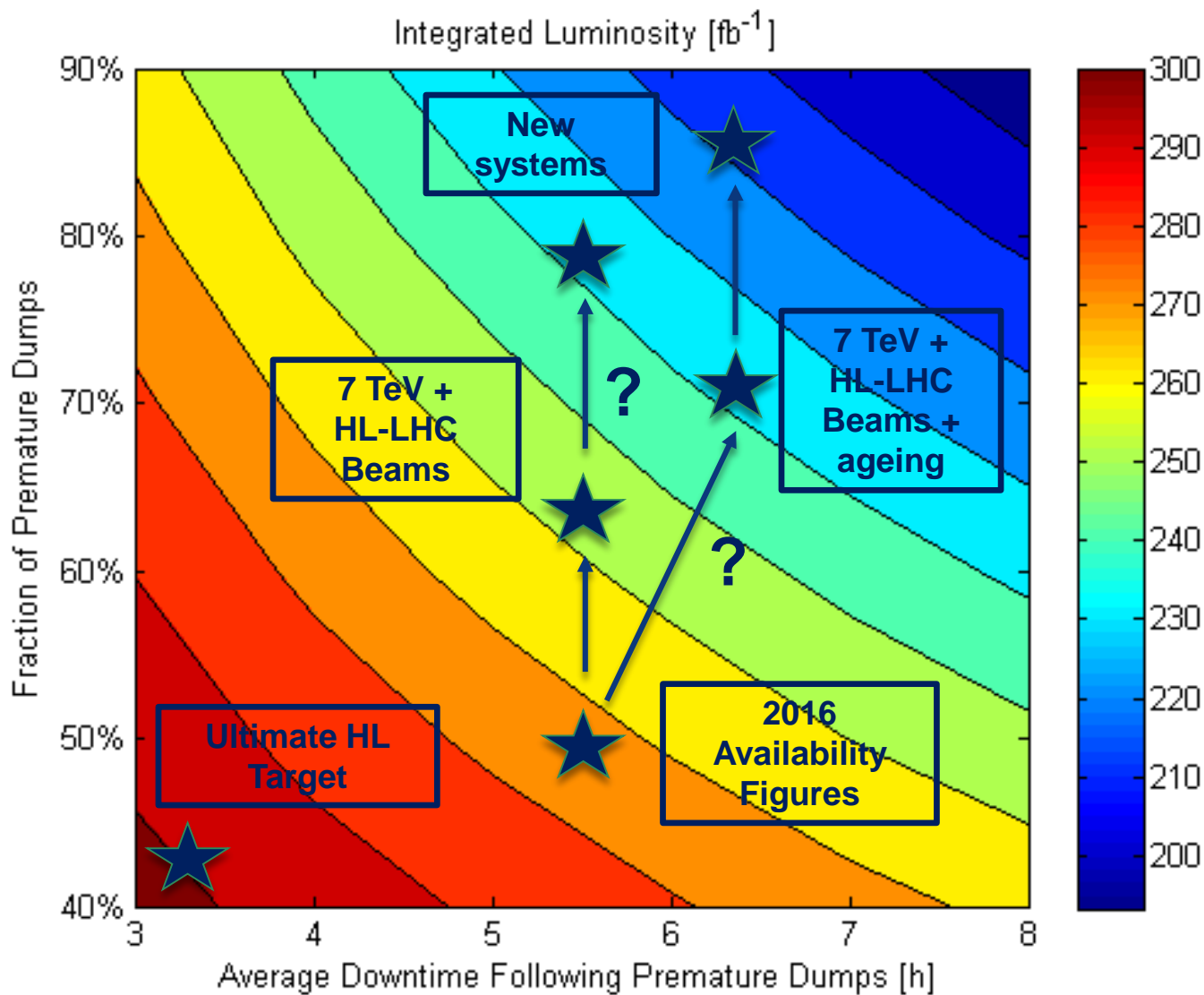
Production in simulation



- Actual production vs. one model round
- Note the intensity ramp up at start of the year
- Assumptions: e.g. constant time between TS → Visual differences in actual and modelled productions



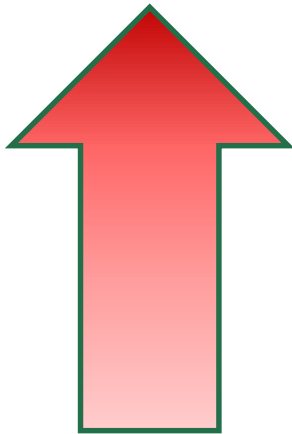
- Luminosity production distribution based on 1000 simulation rounds
- Simulation result: 23.38 fb<sup>-1</sup> sufficiently close to actual production 23.27 fb<sup>-1</sup>



# Machine Protection

# Hazard Analysis: Top-Down or Bottom-Up?

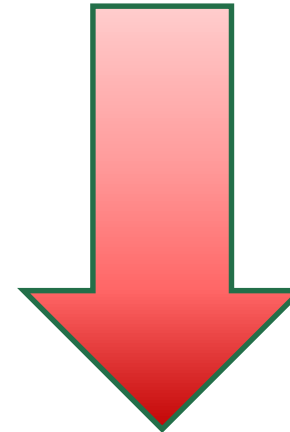
**Consequences of  
component  
failure on system  
behaviour**



**Component Level**

- **Maybe impractical for large projects**
- **Limited to 'component failures'**

**Definition of high  
level accidents /  
failure scenarios**

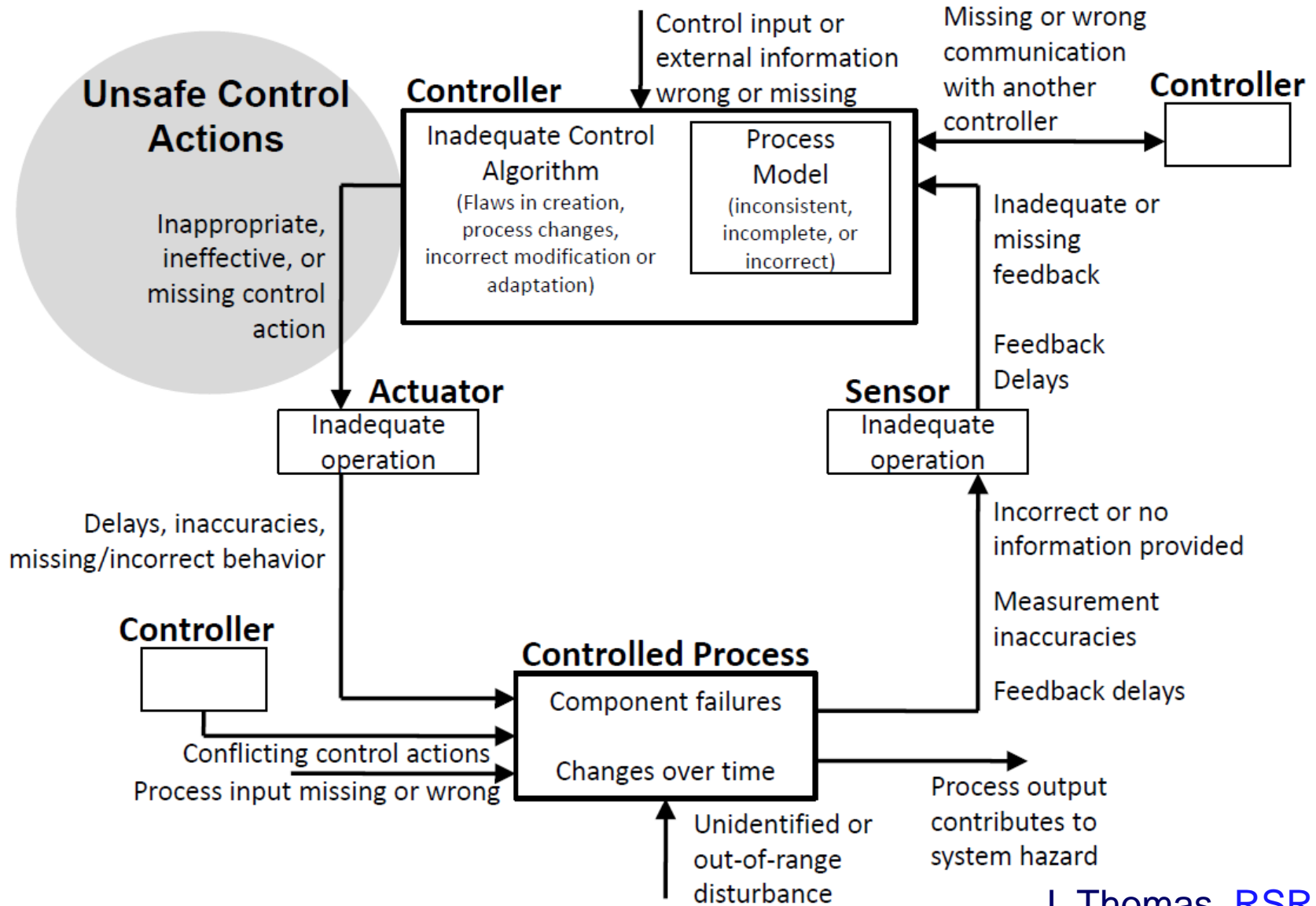


**Identification of  
causal factors  
leading to accidents**

- **Suitable for increasing complexity**
- **Extends further than 'component failures'**

- ❑ Increasing **accelerator complexity** requires a systematic approach for identification of machine protection requirements
  - Address and optimize **contradictory requirements** (safety vs availability)
  - Applicable from **early design** stages (not applied to a given design)
  - Results should not regard only the **system architecture**, but also provide recommendations for correct **operation and management** of the accelerator
  
- ❑ Long-term goal:
  - Identify suitable method for the design of machine protection systems for the **next generation** of particle accelerators
  
- ❑ As a start...
  - Apply method for the **first time to a small accelerator** to verify its suitability → Linac4

# Identify Causal Factors



J. Thomas, [RSRA2015](#)



# Step 4: Causal Factors

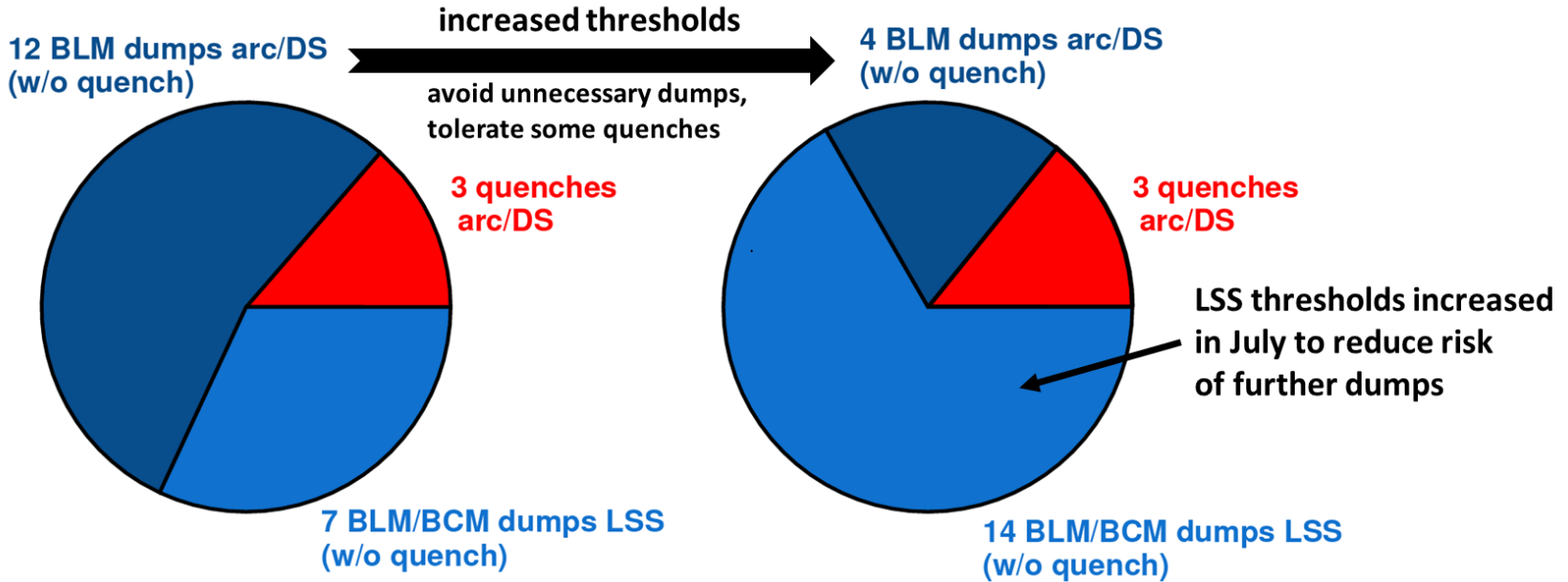
UCA: a beam stop is executed when it is not necessary			
Scenario	Associated Causal Factors	Notes	Requirements
[Control input or external information wrong or missing]  Operators trigger an unnecessary beam stop	Operators accidentally act on the physical device connected to the controller	The emergency button in the control room is accidentally pushed	Protect the physical device from accidental contact
	Operators misinterpret feedback from instrumentation and trigger the beam stop	The operator misinterprets a signal judging it as a relevant deviation from the nominal configuration and decides to stop the beam for safety reasons	Train operators to use softwares and processes running in the control room
	Operators act on a command that triggers a dangerous situation and thus a beam stop	The operator tries to compensate a beam or hardware setting but this leads to a dangerous state that requires a beam stop	Train operators to use softwares and processes running in the control room
	Technical personnel tries to access the linac while it is working, causing a beam stop	Technical personnel is unaware that the machine is running and tries to access it	Require authorization from the control room for machine access
[Sensor - Inadequate or missing feedback]  The sensor feedback is wrong and automatically triggers a beam stop	Sensor is faulty and causes a beam stop	A sensor signals its faulty state and determines a beam stop, even if no direct machine harm exists	A dedicated reliability analysis can assess what is the ideal number and type of sensors to be used to minimize the occurrence of false or missed detections (see chapter on calculation of interlock loop architectures)
	Spurious trigger of a sensor causing a beam stop	A sensor signals a hazardous operating condition due to a spurious failure (e.g. radiation-induced)	Consider adding redundancy.  When possible, locate sensors and instrumentation far from radiation-exposed areas

- **‘Practical’ measures**
- **Managerial and organizational measures**
- **Procedural measures**
- **Technical requirements: trigger further analyses with traditional methods**

# Protection vs Availability

2015 (22 events - 700h SB)

2016 (21 events - 1800h SB)



- Number of dumps & quenches depends on:
  - BLM threshold settings
  - UFO rates -> strong conditioning observed since Oct 2015, rates much lower in 2016 than in 2015

- Arcs and dispersion suppressors:

If we try to prevent quenches, unnecessary dumps are unavoidable

For availability it is better to avoid unnecessary dumps, tolerate some quenches, as confirmed by 2016 experience:

	Actual 2016 - Thresholds 3x above quench level	If we would have applied a quench-preventing strategy
<b>Dumps</b>	<b>4*</b>	<b>71**</b>
<b>Quenches</b>	<b>3</b>	<b>1 (UFO too fast)</b>

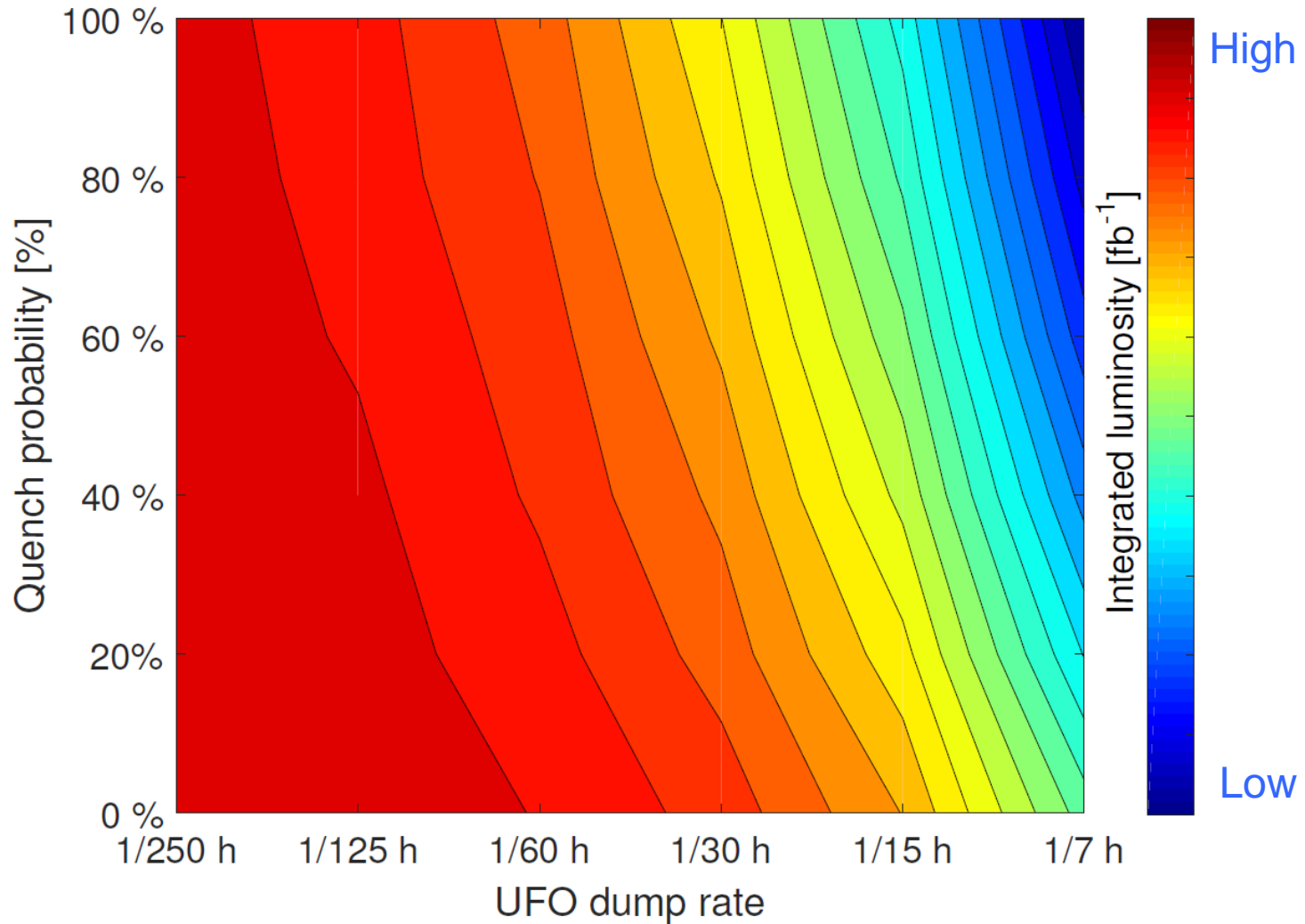
\*3 out of 4 dumps were in S12 (temporary reduction of thresholds due to suspected inter-turn short)

\*\* Simple count of 2016 fills which would have been prematurely dumped if tenfold lower thresholds would have been applied in all sectors throughout the whole year. Multiple occurrences per fill are only counted once.

Would adopt same strategy at 7 TeV -> “only” consequence is increased risk of quenches

- Long straight sections:

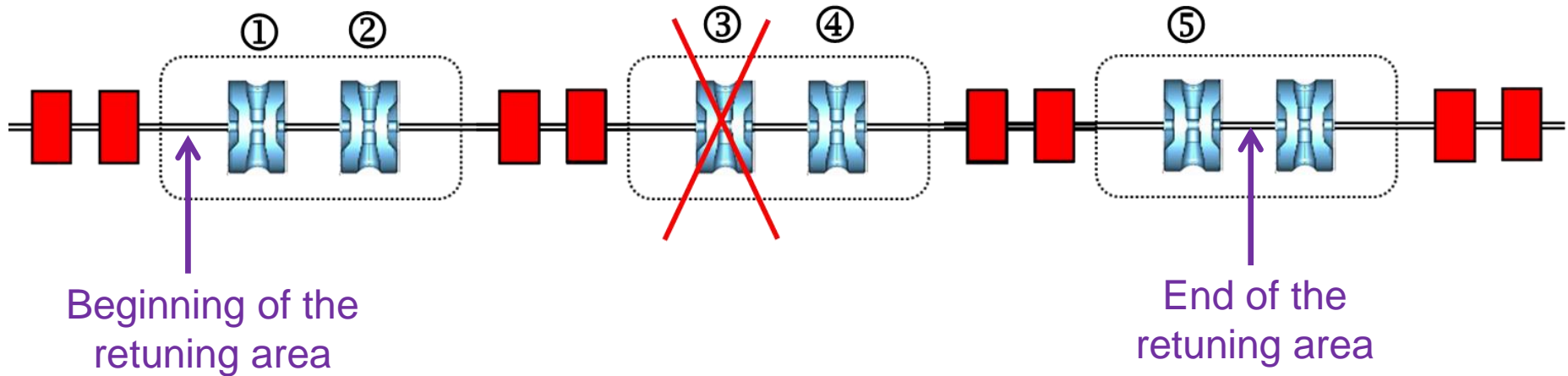
Expect that local UFO hot spots can be mitigated with threshold increase (as done in 2015 and 2016)



# ADS: An Exceptional Case

- In most of the accelerators it is frequent to experience **preventive shutdowns** of accelerator operation in case of equipment failures
- A preventive shutdown for ADS is considered to be a **SCRAM**
- Huge **thermal stresses** induced in the reactor following a SCRAM
- In addition, ~24 h needed for recovery of operating conditions due to legal procedures
- Limited number of SCRAMs tolerated → avoid 'false failures'
- For example: for MYRRHA all failures in the accelerator lasting more than 3 s potentially lead to a SCRAM

# Solution: Dynamic Failure Compensation



- **1<sup>st</sup> criterion:** recover the same transfer matrix of the retuned area than in nominal condition
- **2<sup>nd</sup> criterion:** the total Energy gain should remain the same than in the nominal case
- **3<sup>rd</sup> criterion:** the time of flight should remain the same than in the nominal case

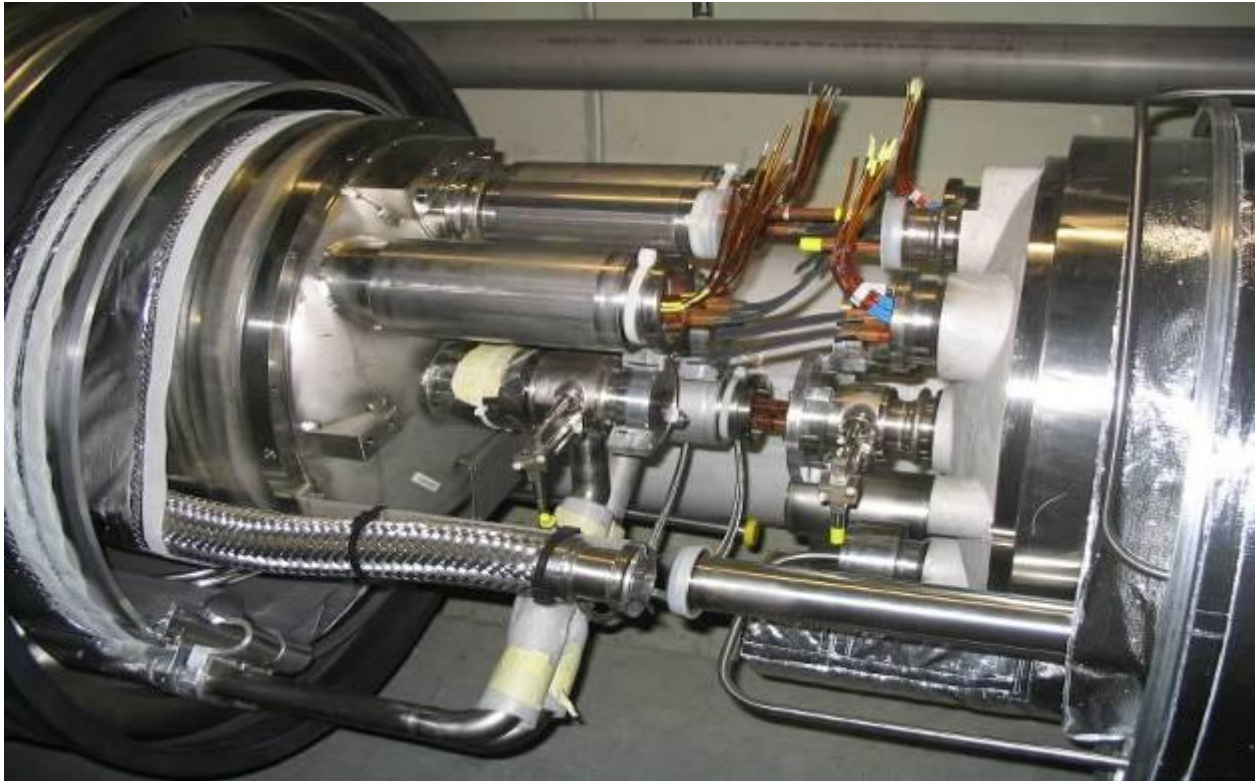
To be done in less than 3 seconds for MYRRHA...

# **Additional Factors Influencing the Achieved Protection Level**



# The incident of 19 September 2008

- **10000** high current superconducting **cable joints** – all soldered in situ in the tunnel and **one** of these connections was **defective**

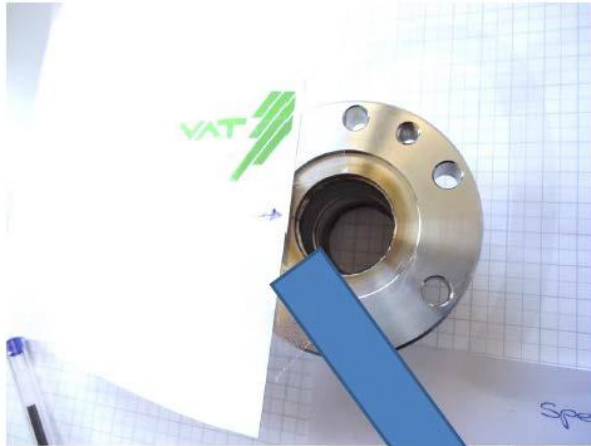


- **One joint ruptured, with 600 MJ stored in the magnets – 70% of this energy was dissipated in the tunnel, electric arcs, vaporizing material, and moving magnets around**

# The incident of 19 September 2008



Other factors play a role: quality assurance, time constraints,...



## L4 damage bellows



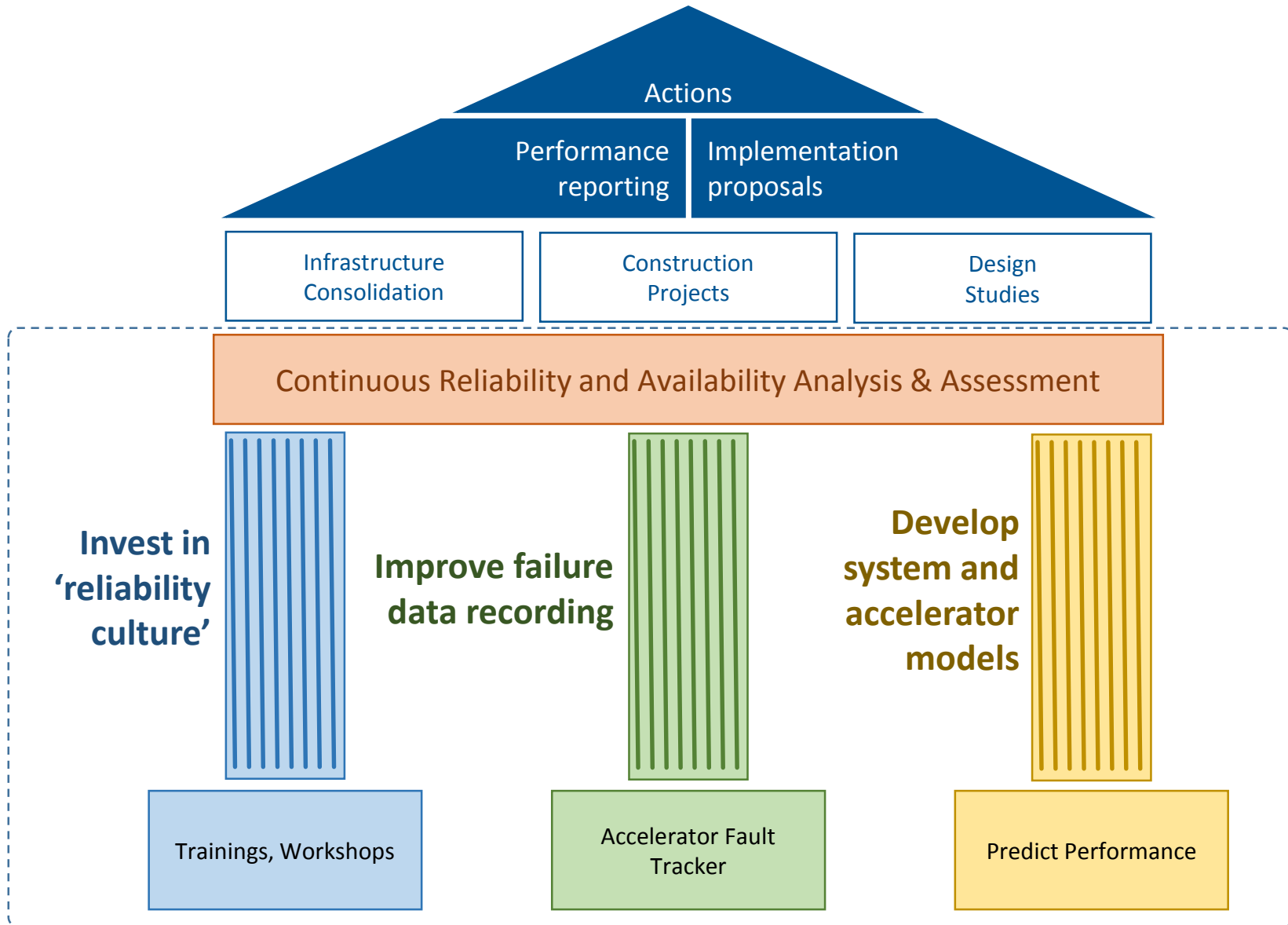
- 1) Severe misalignment between the RFQ and the MEBT
- 2) Optic that favoured amplification of this misalignment (test)
- 3) Phase advance such that the loss occurred on the “wave” of the bellow (200  $\mu\text{m}$ ) and it is an aperture limitation

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Accidents might occur due to a combination of different factors (change of boundary conditions, non-standard operation, design flaws, human intervention,...)

# Conclusion

# 3 Pillars



- Protection for future High-Power / High-Energy accelerators will be fundamental to prevent long stops due to equipment damage
  - Evaluate methods for the design of the future generation of Machine Protection Systems
- Limiting maintenance actions on accelerator equipment will be a key factor for the success of the next generation of large-scale accelerators
  - Conceive from the design phase systems with a high degree of redundancy and flexibility
  - Reduce only to 'essential' equipment located in the tunnel
  - Invest in advanced diagnostic techniques (e.g. failure prediction via pattern recognition,...)
  - Explore the potential of developments in robotics for remote maintenance
- Optimize accelerator schedules
  - Today for the LHC only ~150 days per year are allocated for luminosity production
  - Design systems thinking about faster commissioning (with and without beam)
  - Limit the number of technical stops (synchronize with injectors)

**Thanks a lot for your attention!!**